

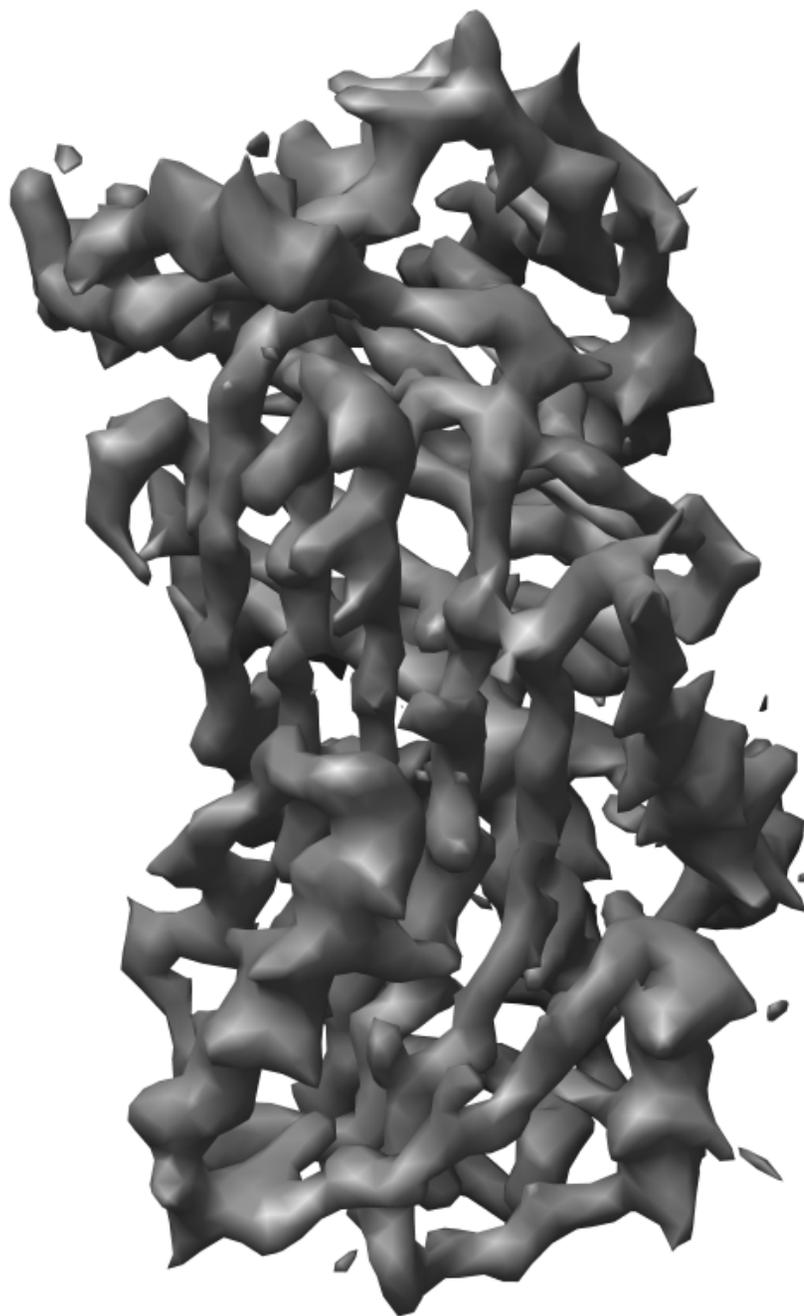
CTF Correction, Resolution and Model Bias

Steve Ludtke
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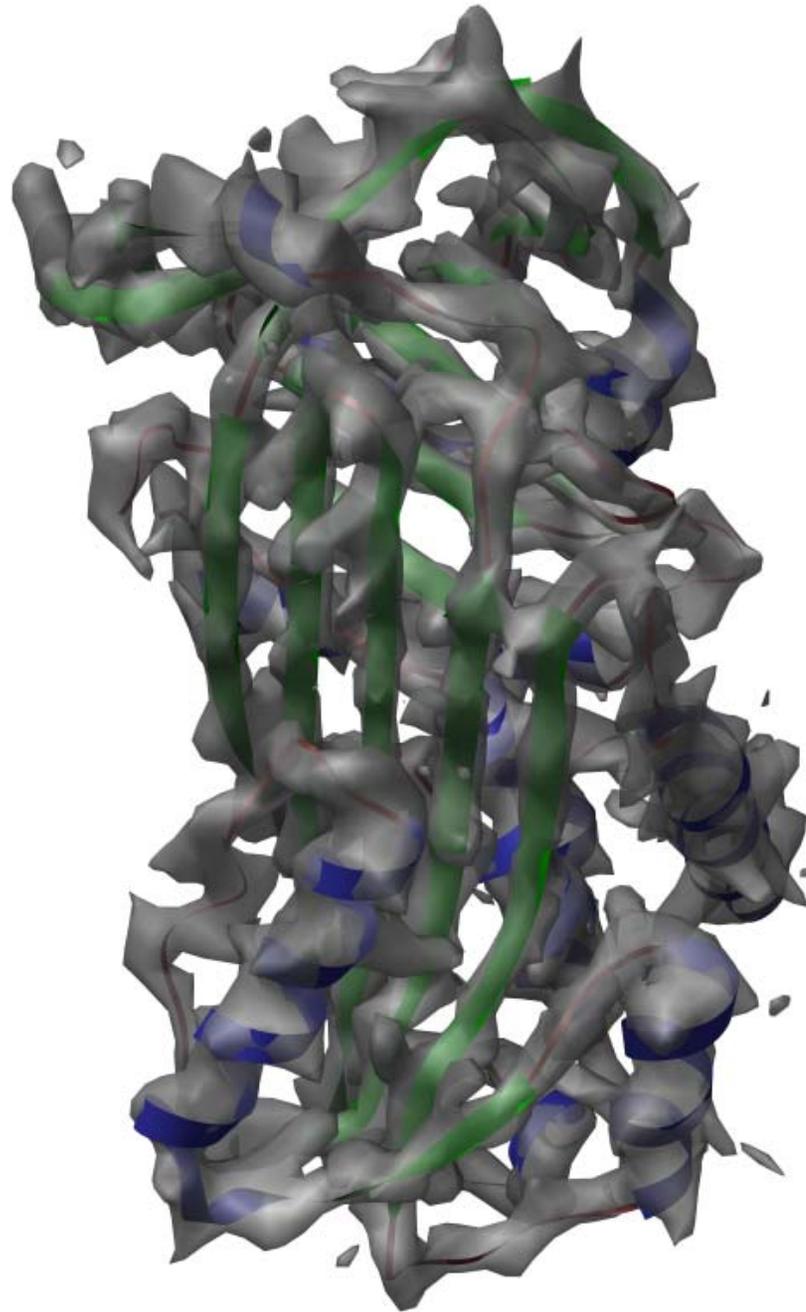
4CAA



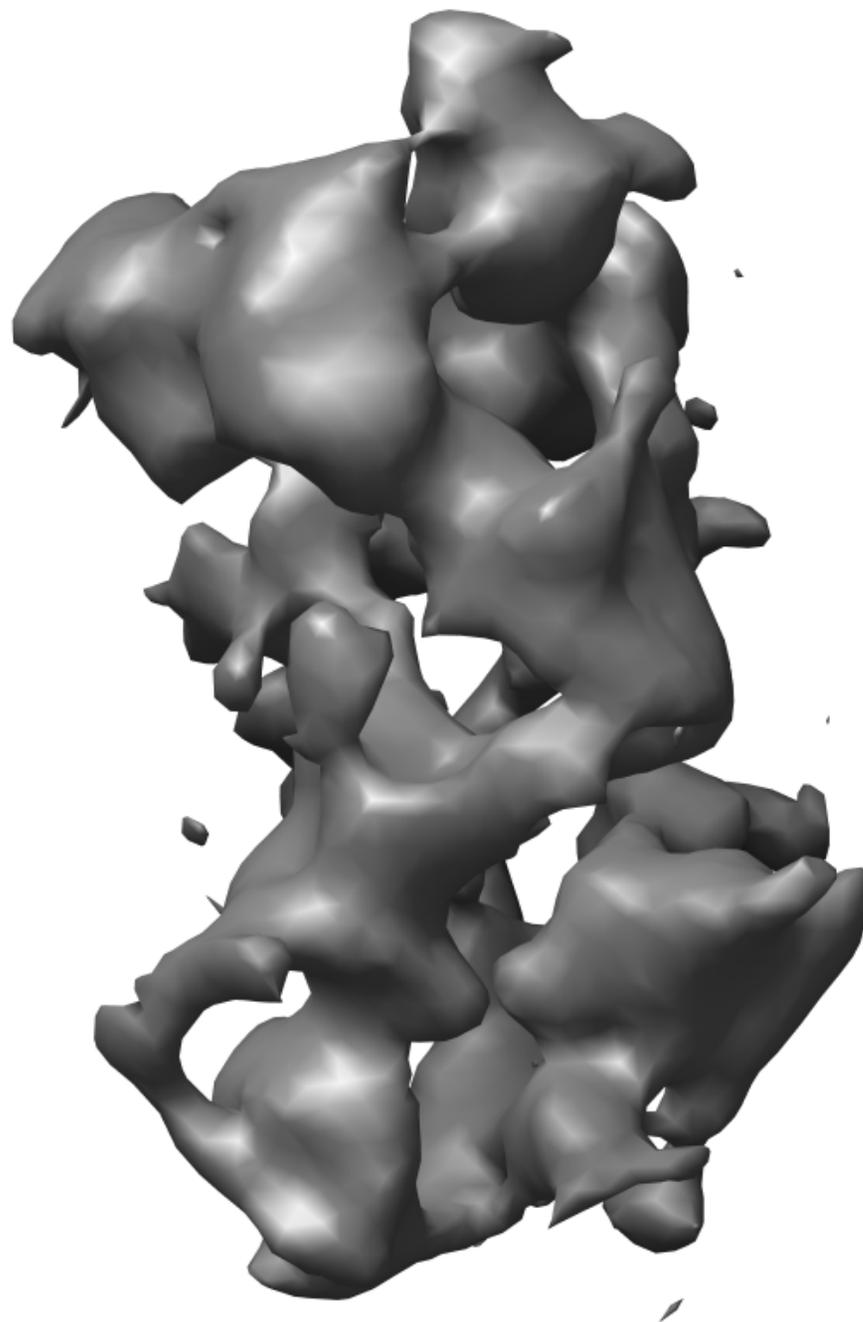
4CAA



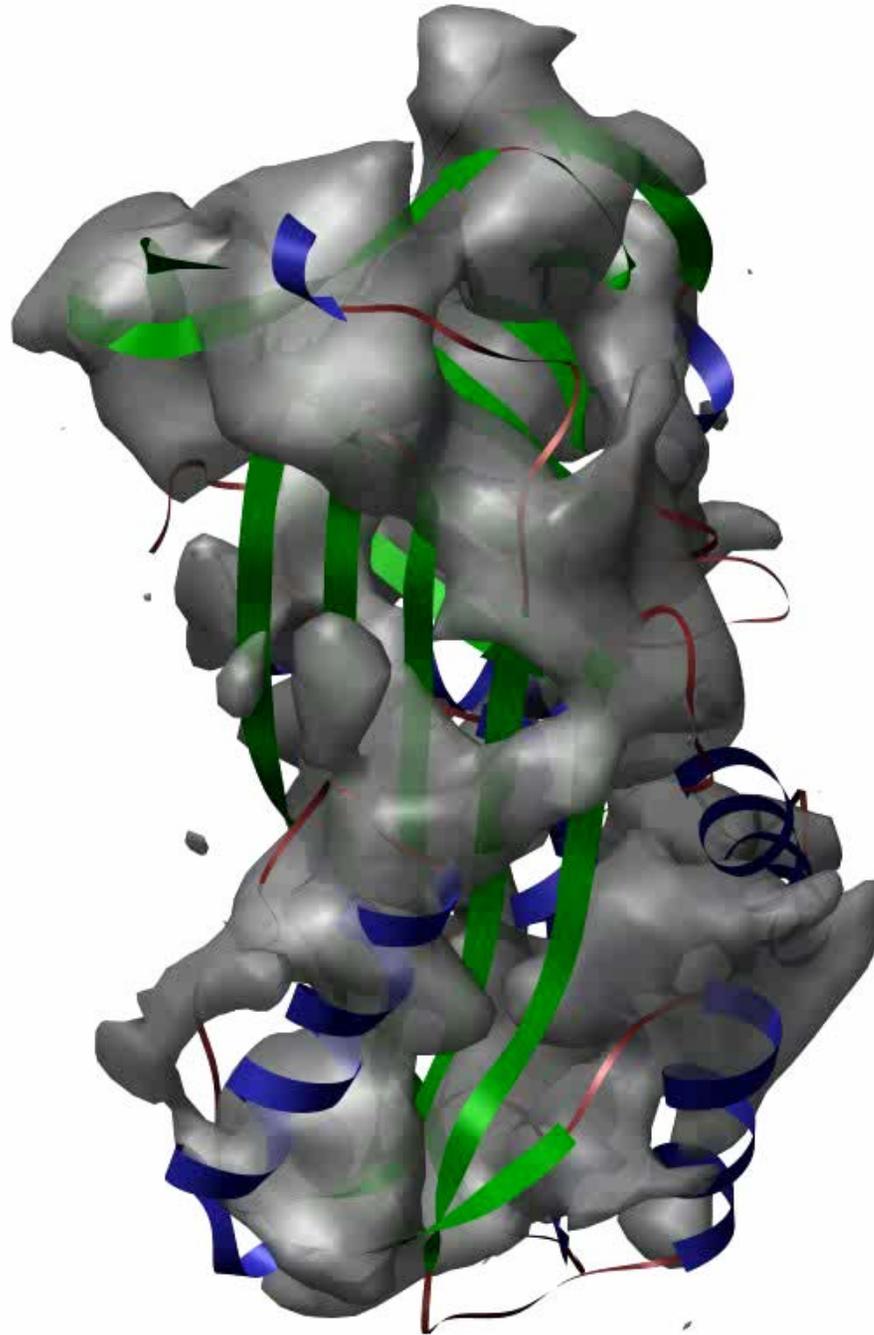
4CAA



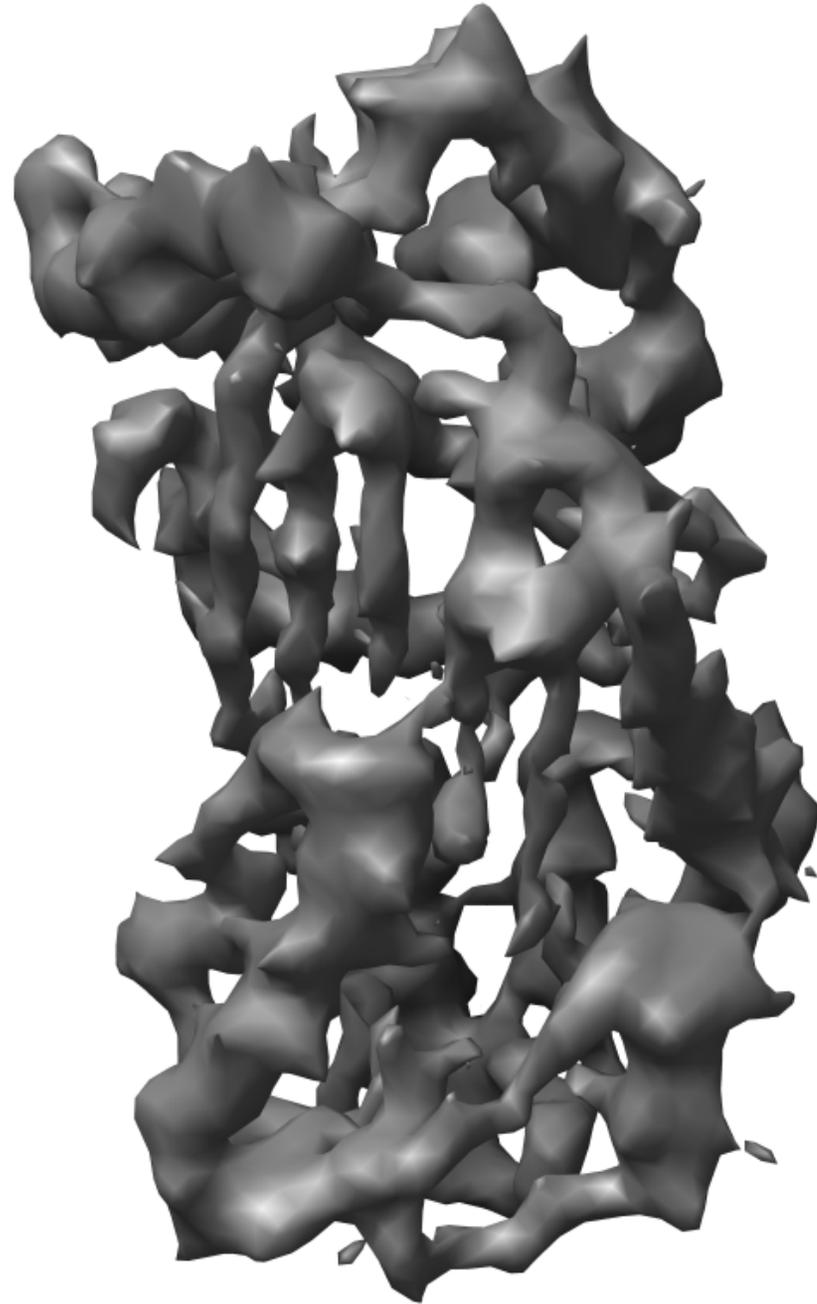
No CTF Corr (1 defocus)



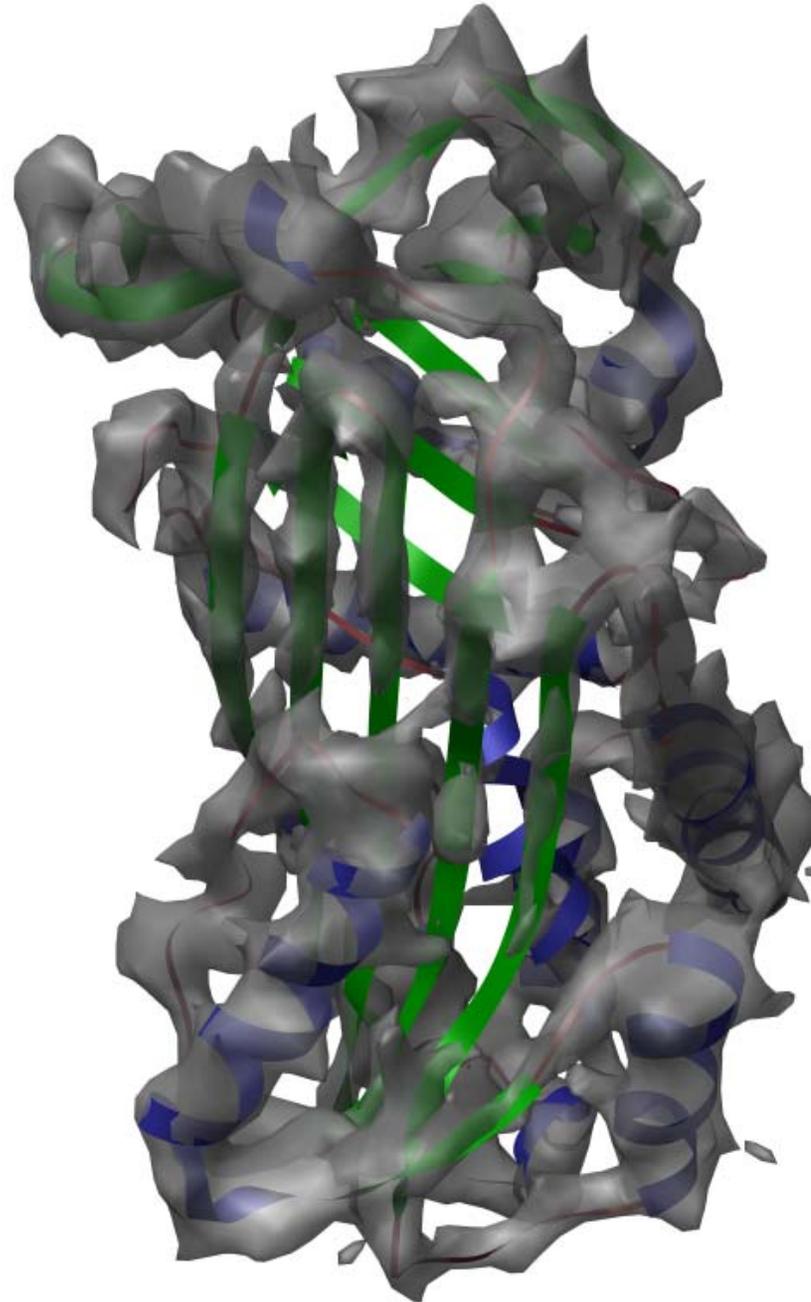
No CTF Corr (1 defocus)



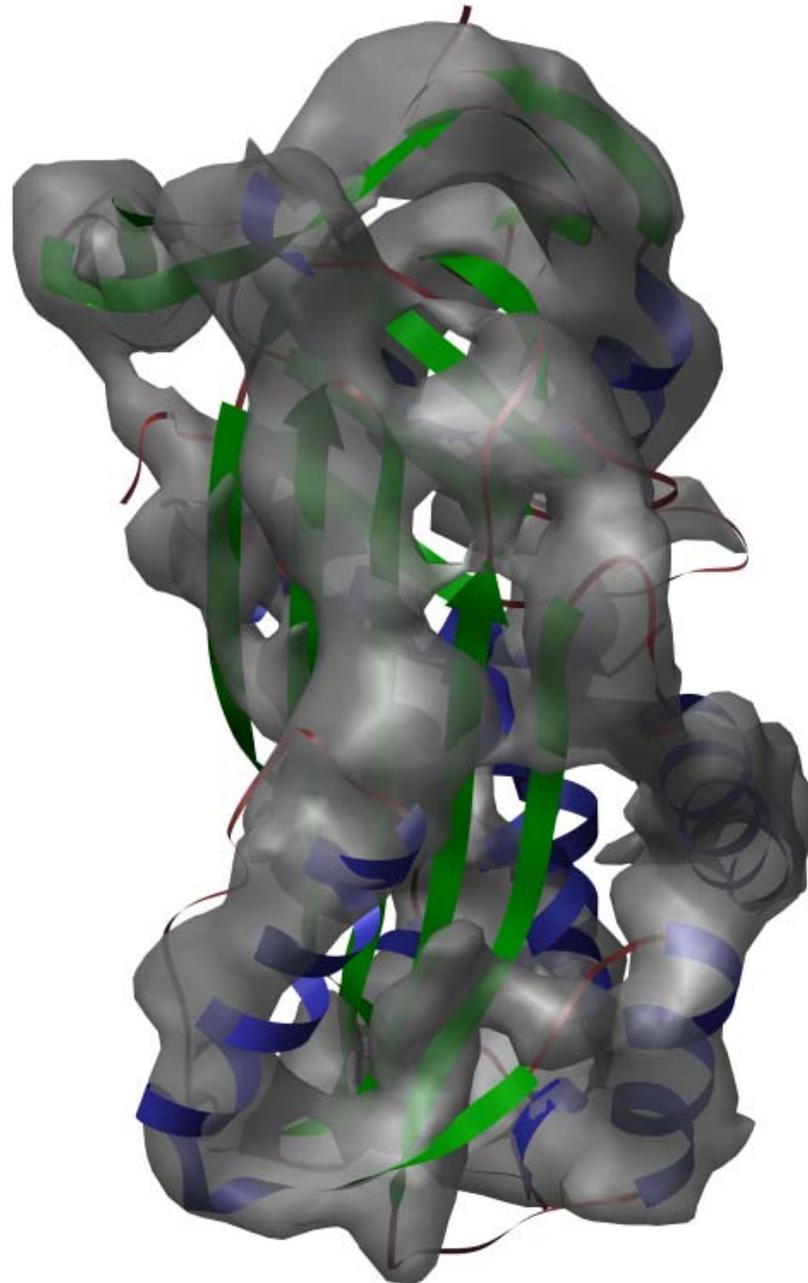
Phase Flipped (1 defocus)



Phase Flipped (1 defocus)

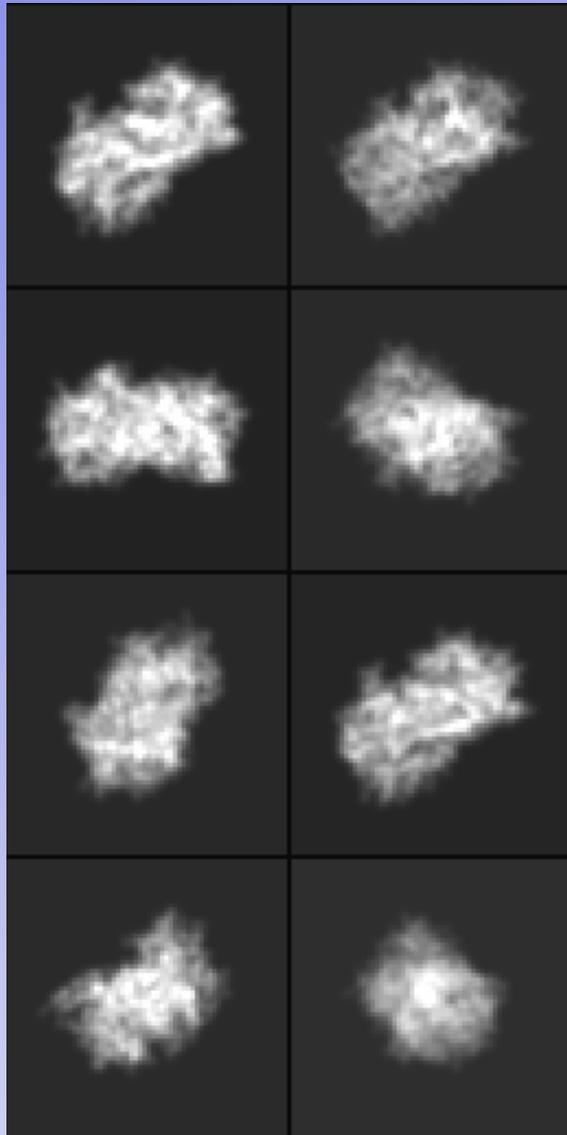


Phase Flipped (mult defocus)

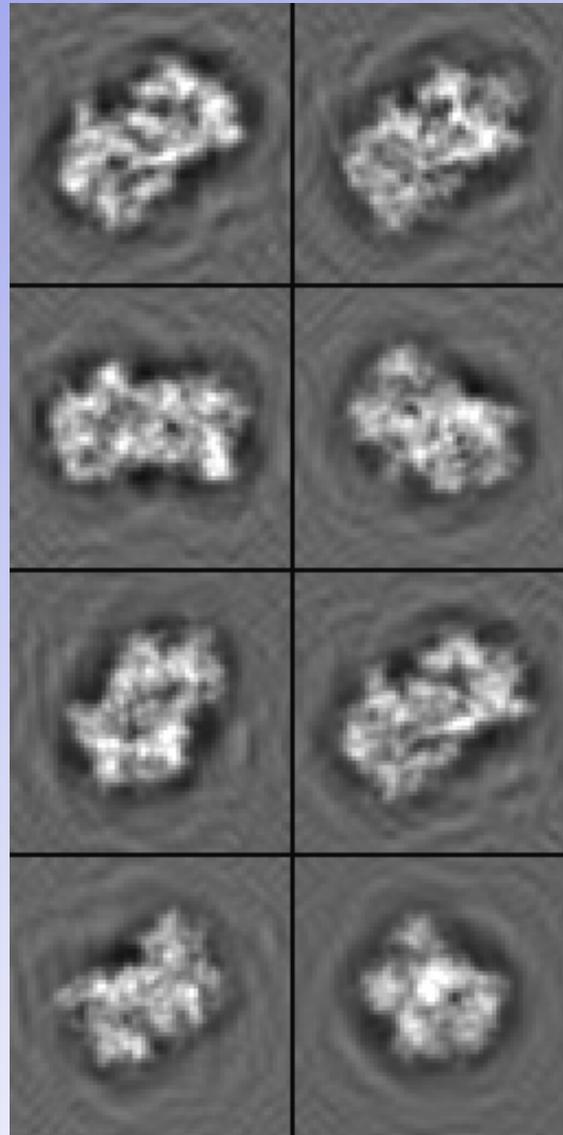


4CAA in 2D

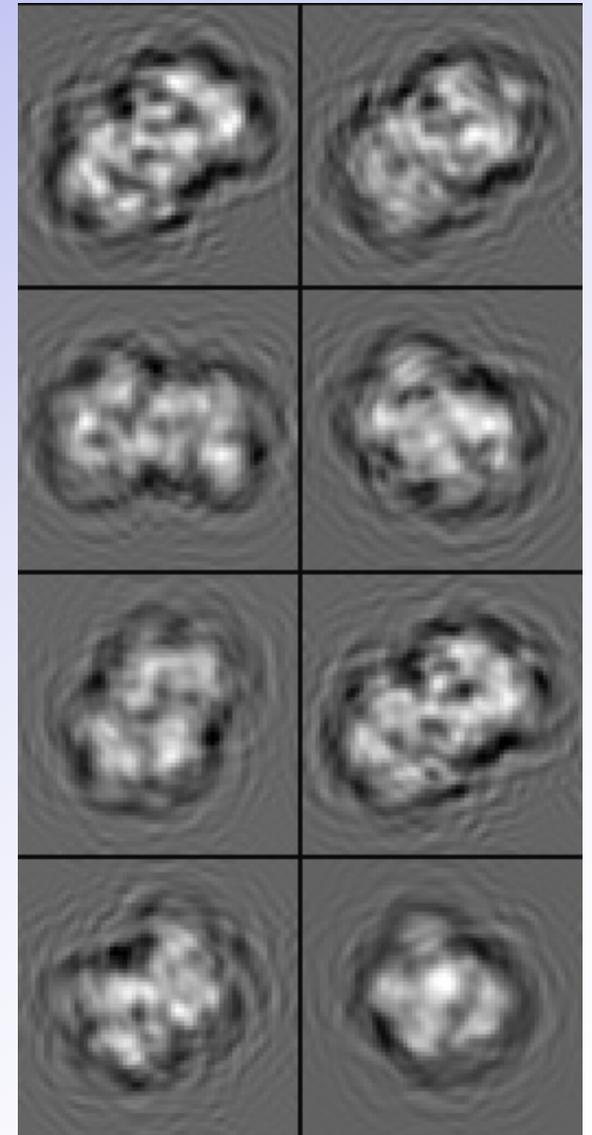
No CTF



CTF Amp



Amp & Pha



CTF Correction

Measured Image

Ideal Particle

Random Noise

$$\overline{M}(s, \theta) = \overline{F}(s, \theta)C(s)E(s) + \overline{N}(s, \theta)$$

$$C(s) = \sqrt{1 - Q^2} \sin \gamma + Q \cos \gamma$$

$$\gamma = -\pi \left(\frac{1}{2} C_s \lambda^3 s^4 - \Delta Z \lambda s^2 \right)$$

$$E(s) = e^{-Bs^2}$$

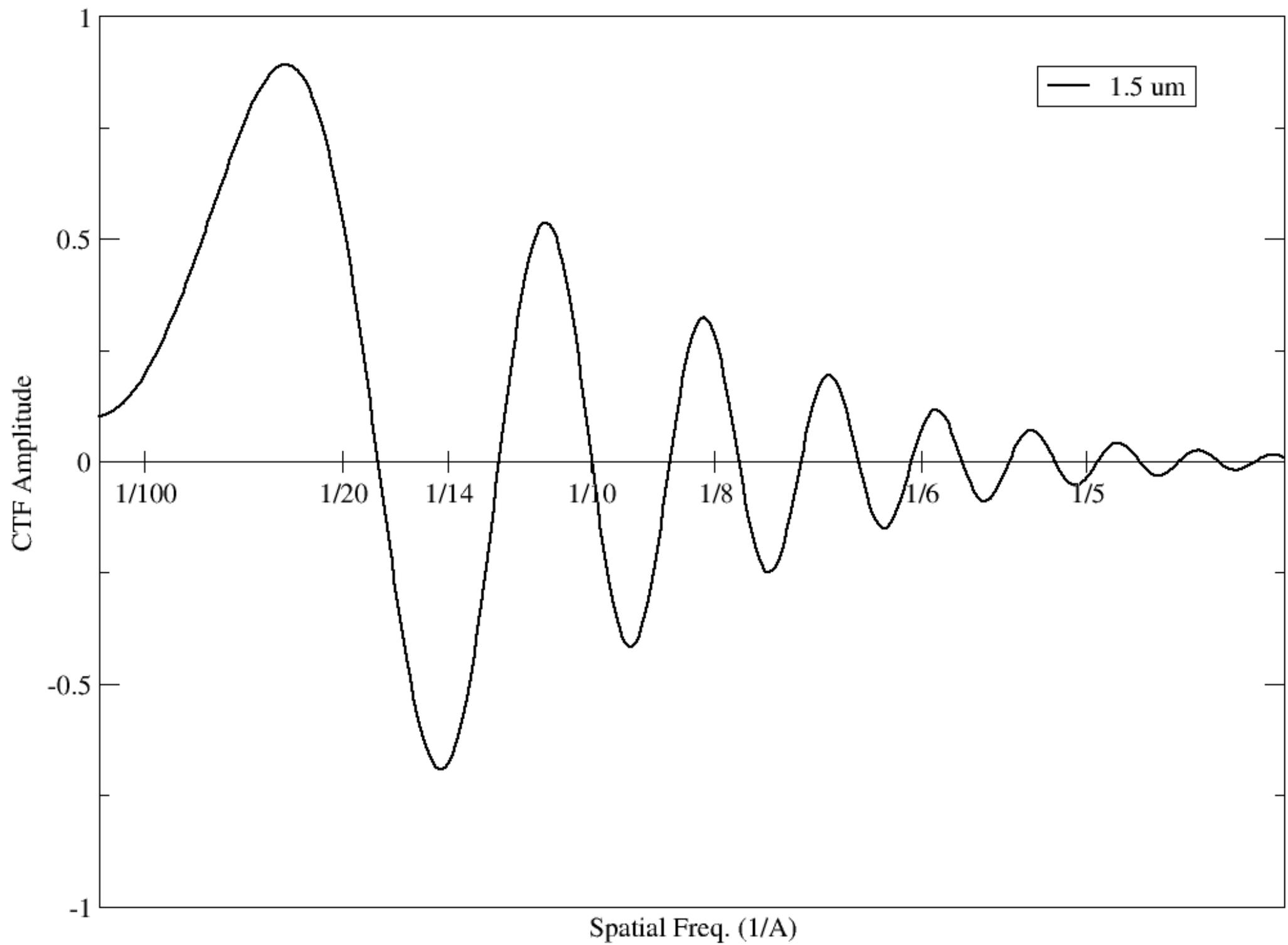
CTF Correction

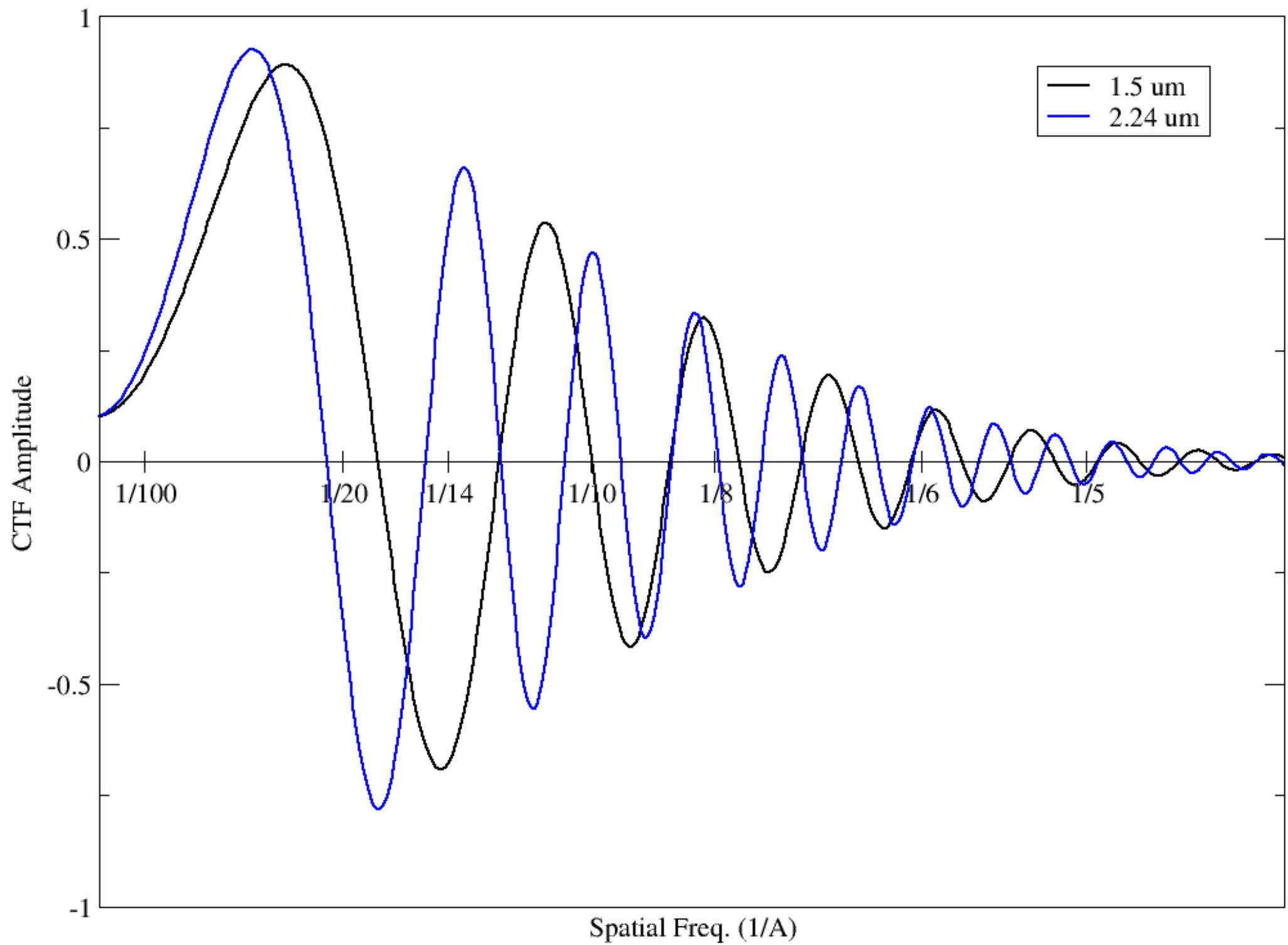
$$\bar{M}(s, \theta) = \bar{F}(s, \theta) C(s) E(s) + \bar{N}(s, \theta)$$

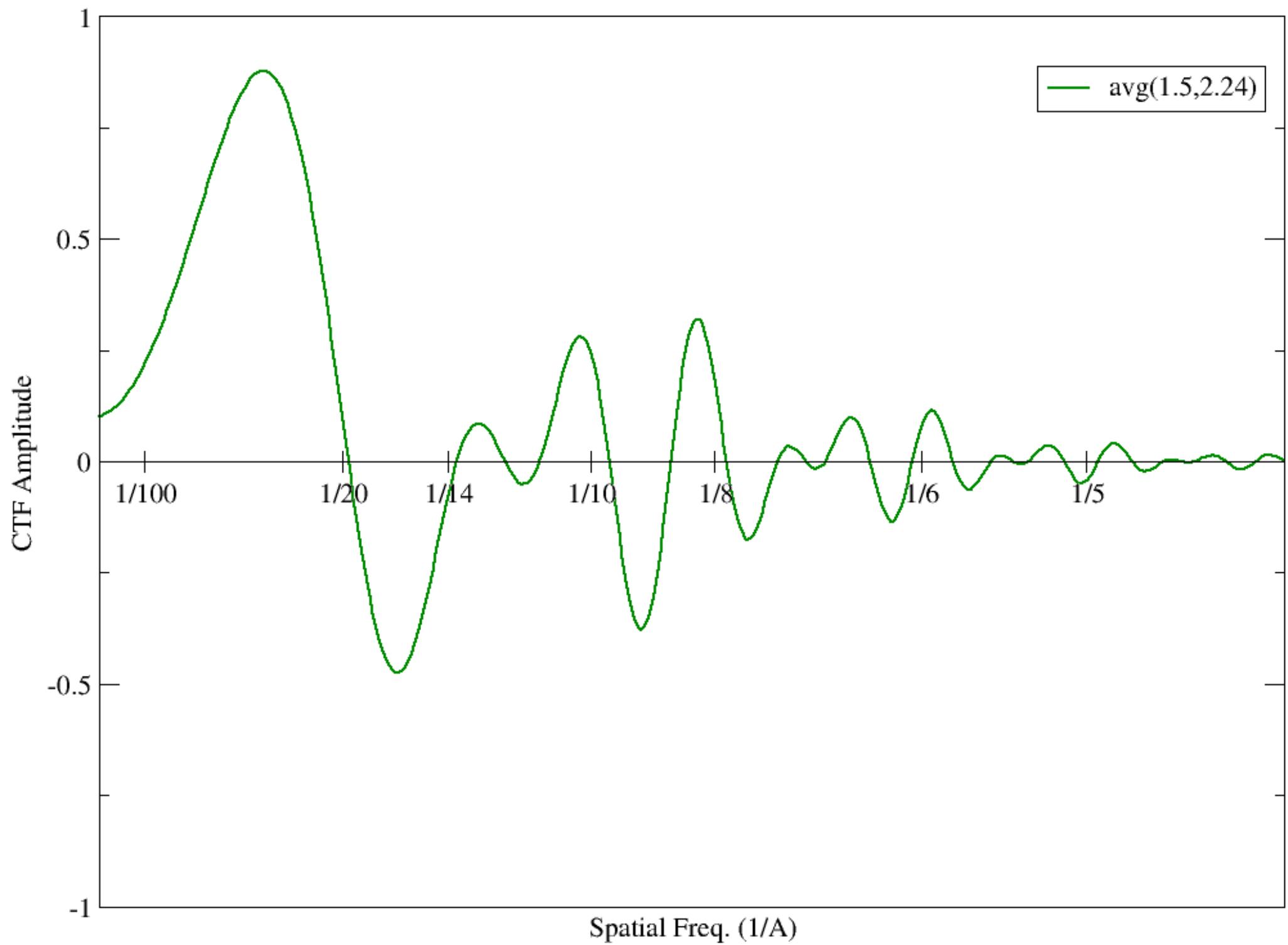
$$C(s) = \sqrt{1 - Q^2} \sin \gamma + Q \cos \gamma$$

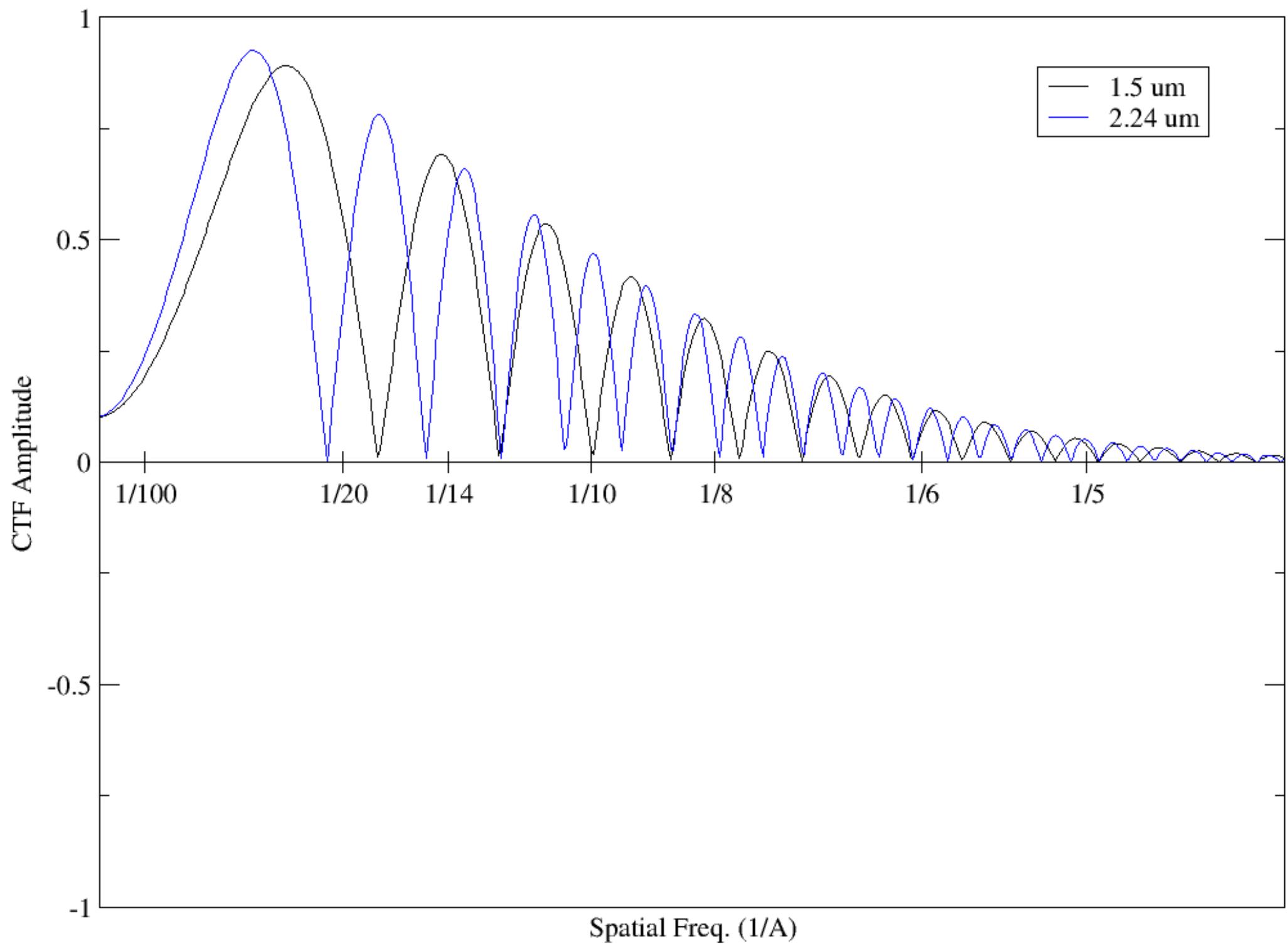
$$\gamma = -\pi \left(\frac{1}{2} C_s \lambda^3 s^4 - \Delta Z \lambda s^2 \right)$$

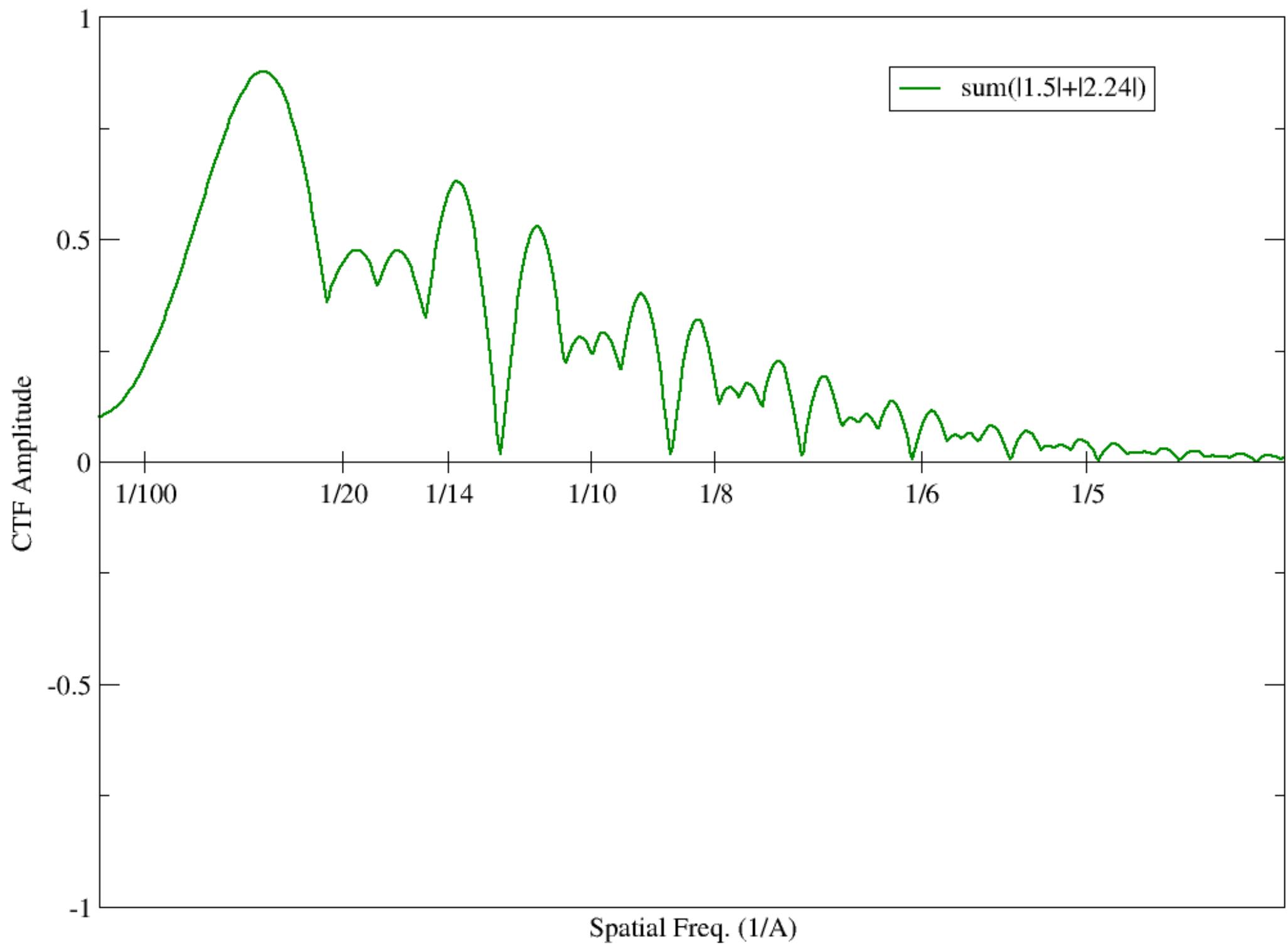
$$E(s) = e^{-Bs^2}$$

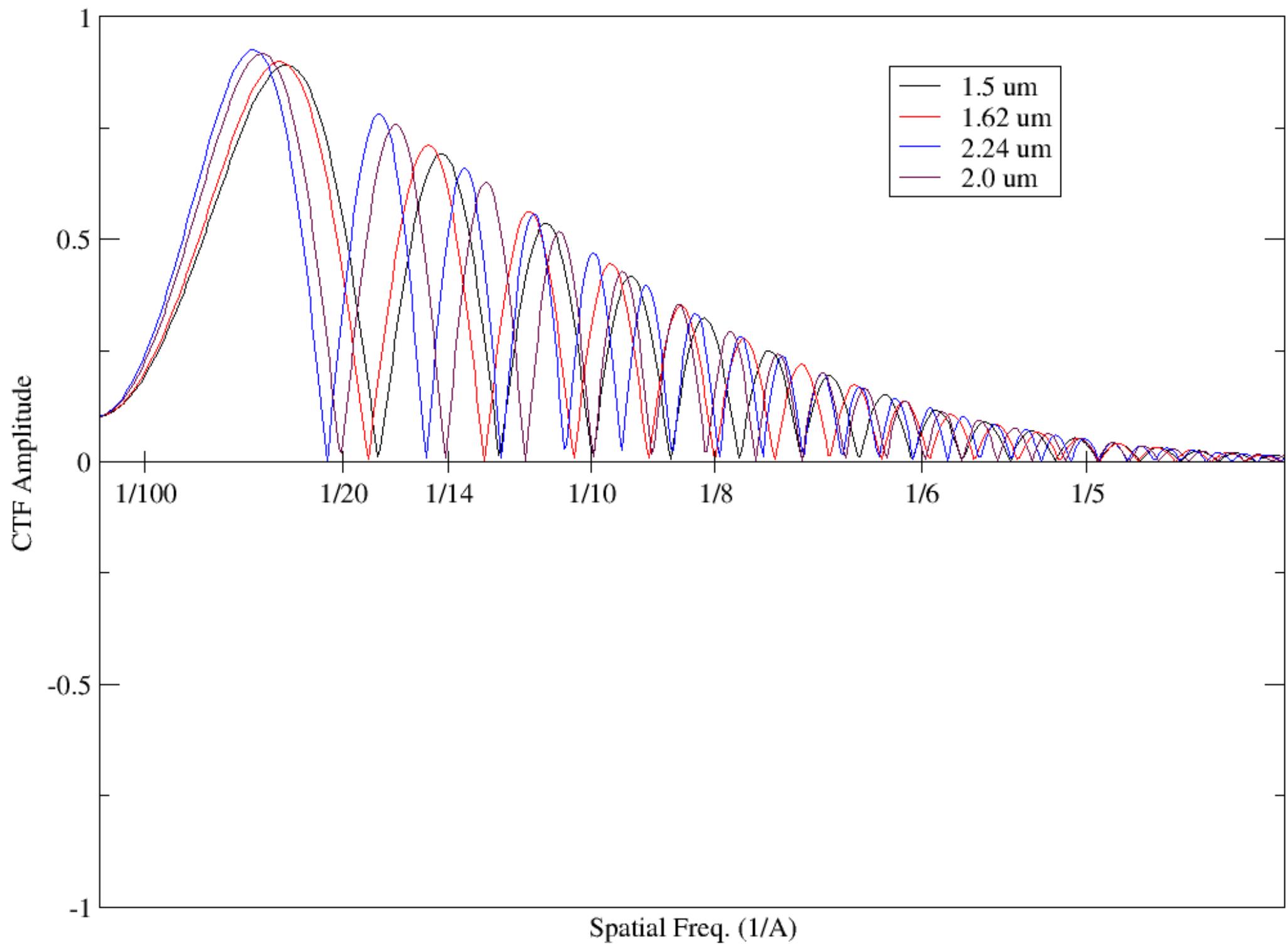


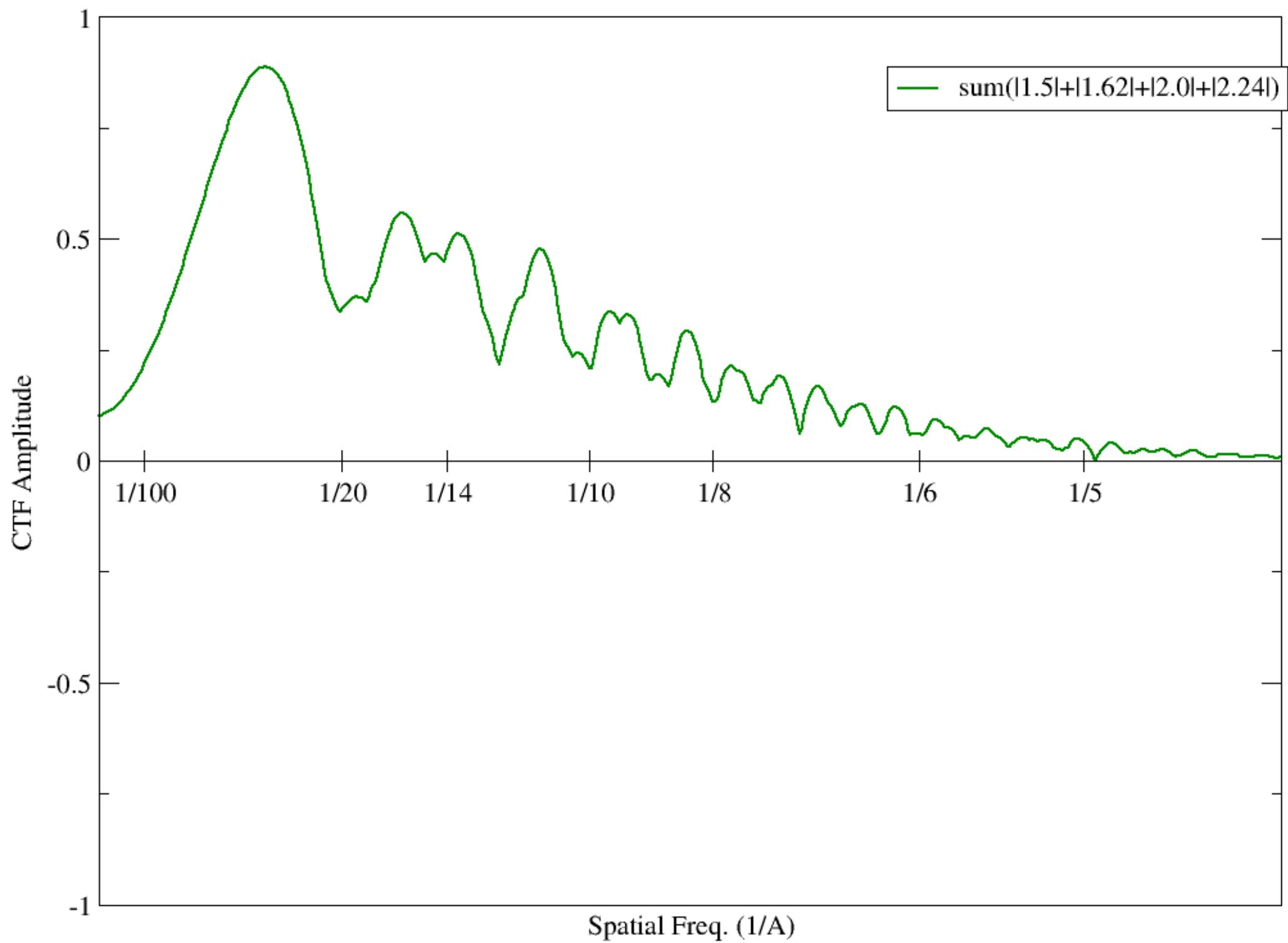












CTF Correction

$$\bar{M}(s, \theta) = \bar{F}(s, \theta)C(s)E(s) + \bar{N}(s, \theta)$$

$$C(s) = \sqrt{1-Q^2} \sin \gamma + Q \cos \gamma$$

$$\gamma = -\pi \left(\frac{1}{2} C_s \lambda^3 s^4 - \Delta Z \lambda s^2 \right)$$

$$E(s) = e^{-Bs^2}$$

$$N(s)^2 = n_1 e^{n_2 s + n_3 s^2 + n_4 \sqrt{s}}$$

$$M(s)^2 = F(s)^2 C(s)^2 E(s)^2 + N(s)^2$$

CTF Correction

Reconstruction

Weight

Measured image

$$\bar{T}(s, \theta) = \sum_i k_i \bar{M}_i(s, \theta)$$

$$k_i = ?$$

- Maximize SNR of $T(s, \theta)$
- Minimize RMSD between T and F

$$\sqrt{\sum_{x,y} (t(x, y) - f(x, y))^2}$$

CTF Correction

Wiener
Filter

CTF
Correction

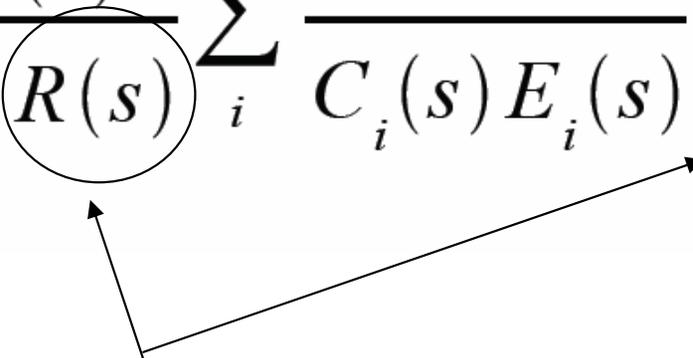
SNR
Weight

$$\bar{T}(s, \theta) = \frac{F^2(s) R(s)}{1 + F^2(s) R(s)} \sum_i \frac{1}{C_i(s) E_i(s)} \frac{R_i(s)}{R(s)} \bar{M}_i(s, \theta)$$

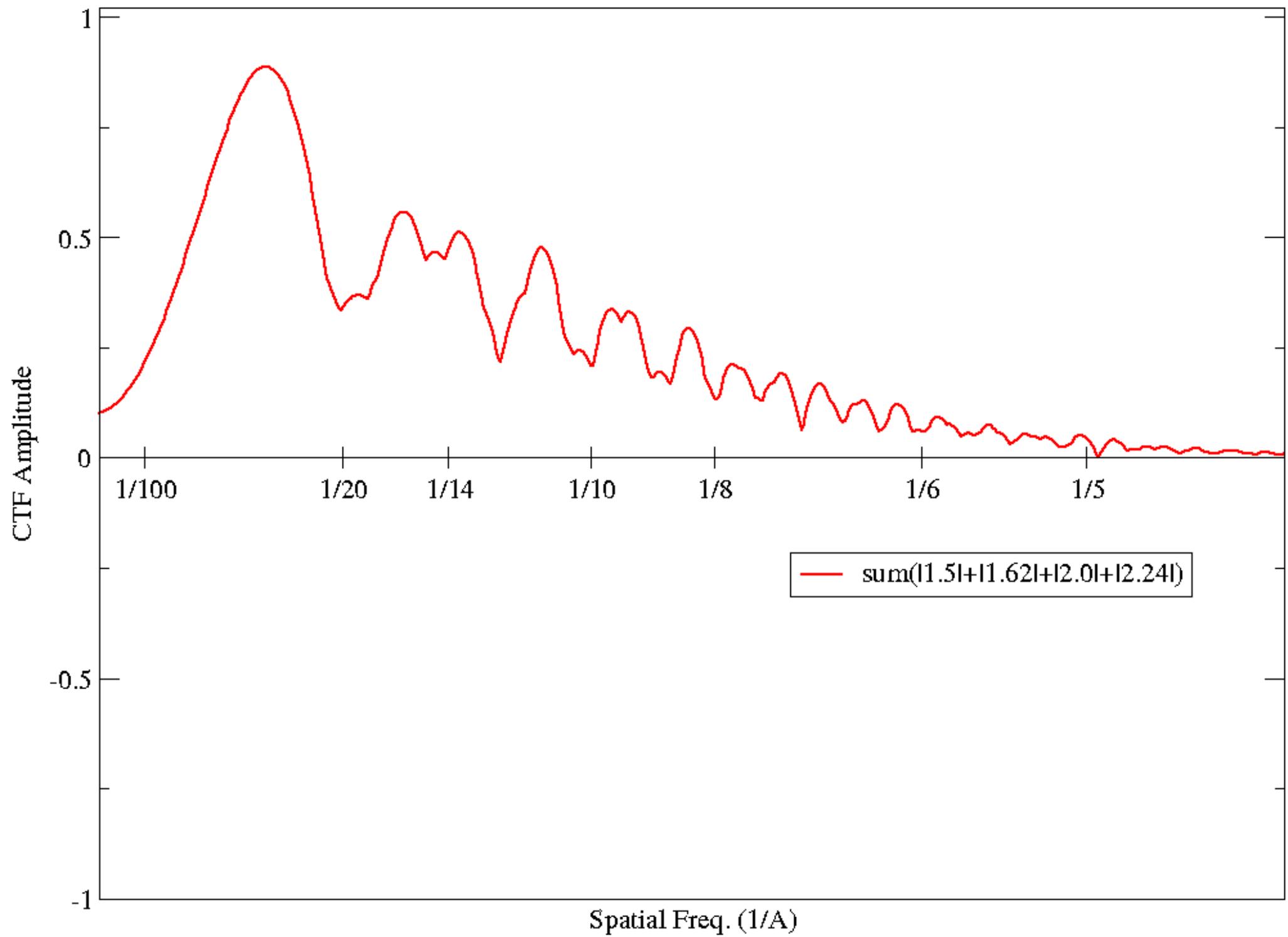
$$R_i(s) = \frac{C_i^2(s) E_i^2(s)}{N_i^2(s)}$$

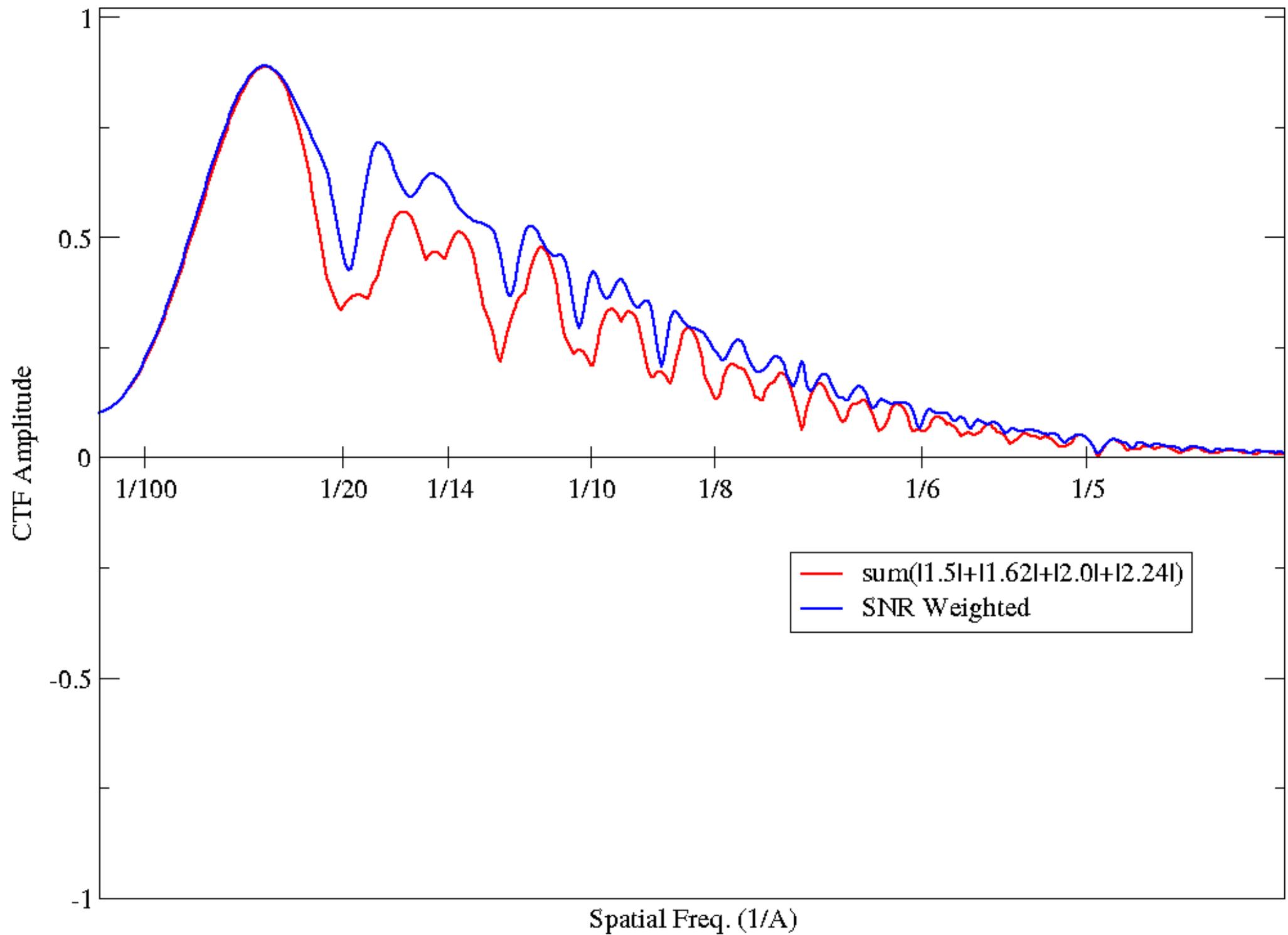
$$R(s) = \sum_i \frac{C_i^2(s) E_i^2(s)}{N_i^2(s)}$$

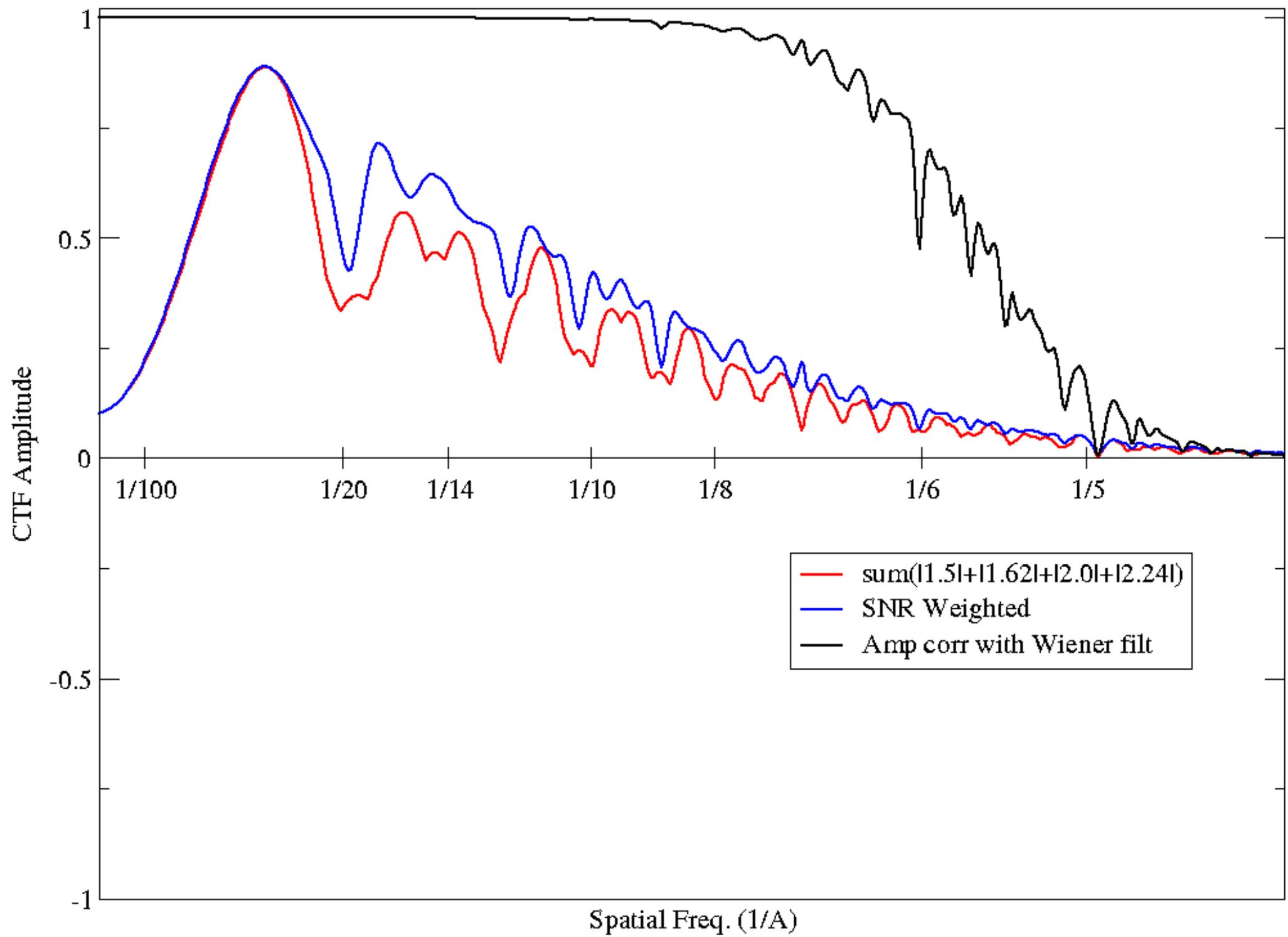
CTF Correction

$$\bar{T}(s, \theta) = \frac{\text{Wiener Filter } F^2(s) R(s)}{1 + F^2(s) \underbrace{R(s)}_{\text{CTF Correction}}} \sum_i \frac{\text{SNR Weight } R_i(s)}{C_i(s) E_i(s) R(s)} \bar{M}_i(s, \theta)$$


Note that this factor depends on ALL of the data and means you cannot 'precorrect' the data then do a reconstruction. You can phase-flip in preprocessing, but Wiener filtration and weighting depend on having all of the data at once.







CTF Correction

$$\bar{M}(s, \theta) = \bar{F}(s, \theta)C(s)E(s) + \bar{N}(s, \theta)$$

$$C(s) = \sqrt{1-Q^2} \sin \gamma + Q \cos \gamma$$

$$\gamma = -\pi \left(\frac{1}{2} C_s \lambda^3 s^4 - \Delta Z \lambda s^2 \right)$$

$$E(s) = e^{-Bs^2}$$

$$N(s)^2 = n_1 e^{n_2 s + n_3 s^2 + n_4 \sqrt{s}}$$

$$M(s)^2 = F(s)^2 C(s)^2 E(s)^2 + N(s)^2$$

8 Parameters

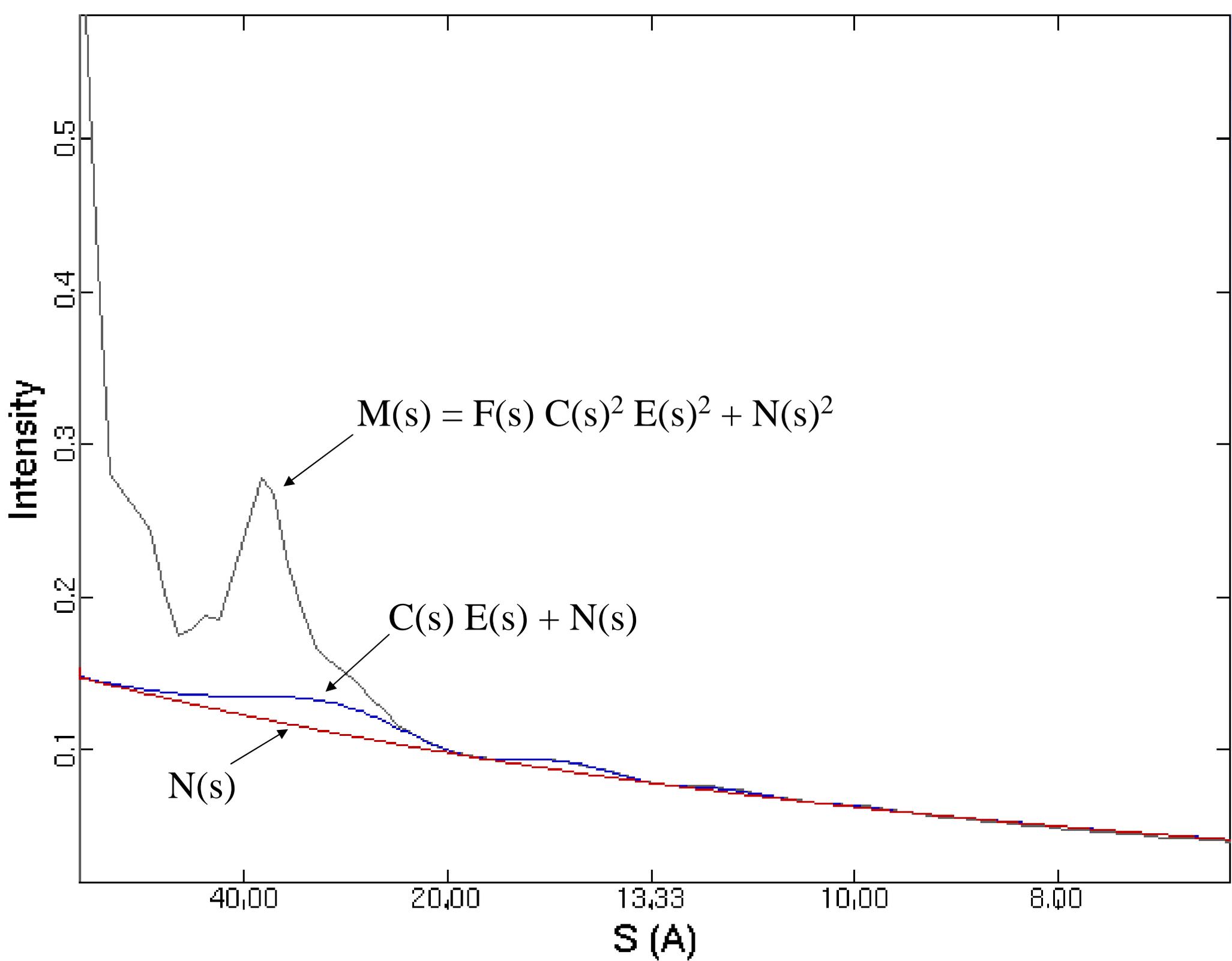
ΔZ - Defocus

Q - Amplitude Contrast

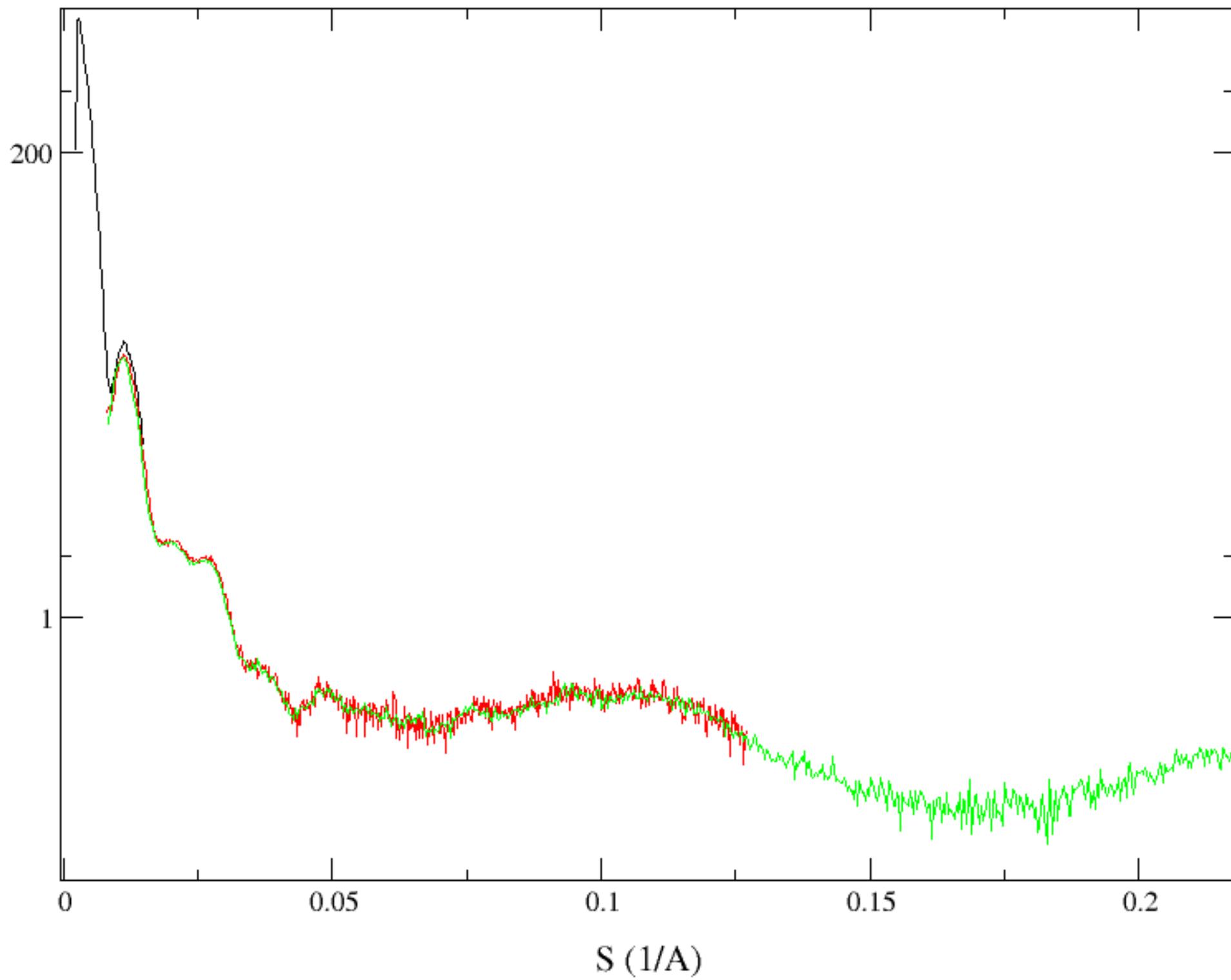
B - Gaussian Envelope Width

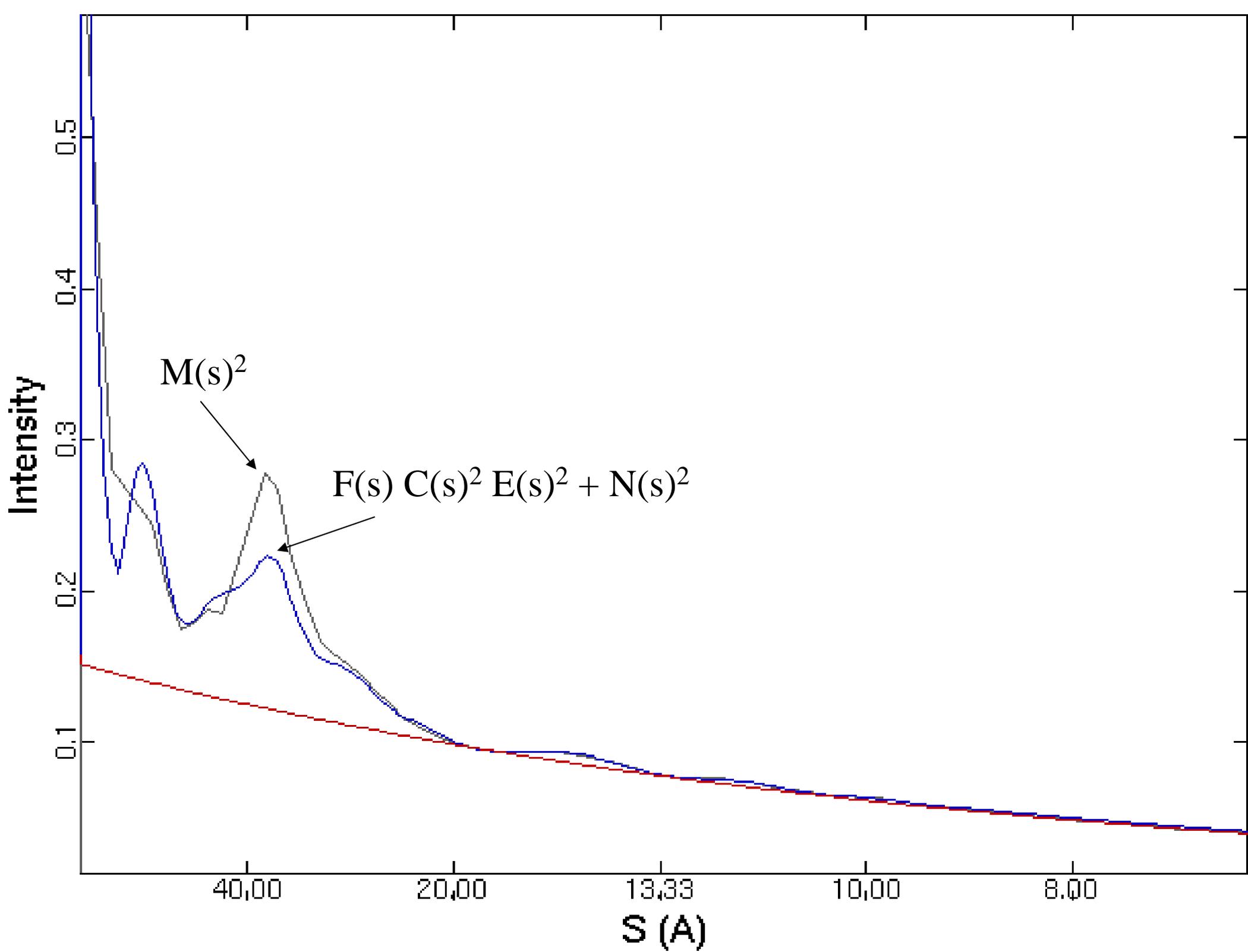
k - Signal Amplitude

n_{1-4} - Noise Parameters



X-ray Scattering Intensity





Resolution vs. Resolvability

- Resolution – a measure of the ability to distinguish between two close but not identical values of the property being measured; it is expressed as the difference in values of a property necessary to make such a distinction; as, a microscope with a resolution of one micron; a thermometer with a resolution of one-tenth of a degree.

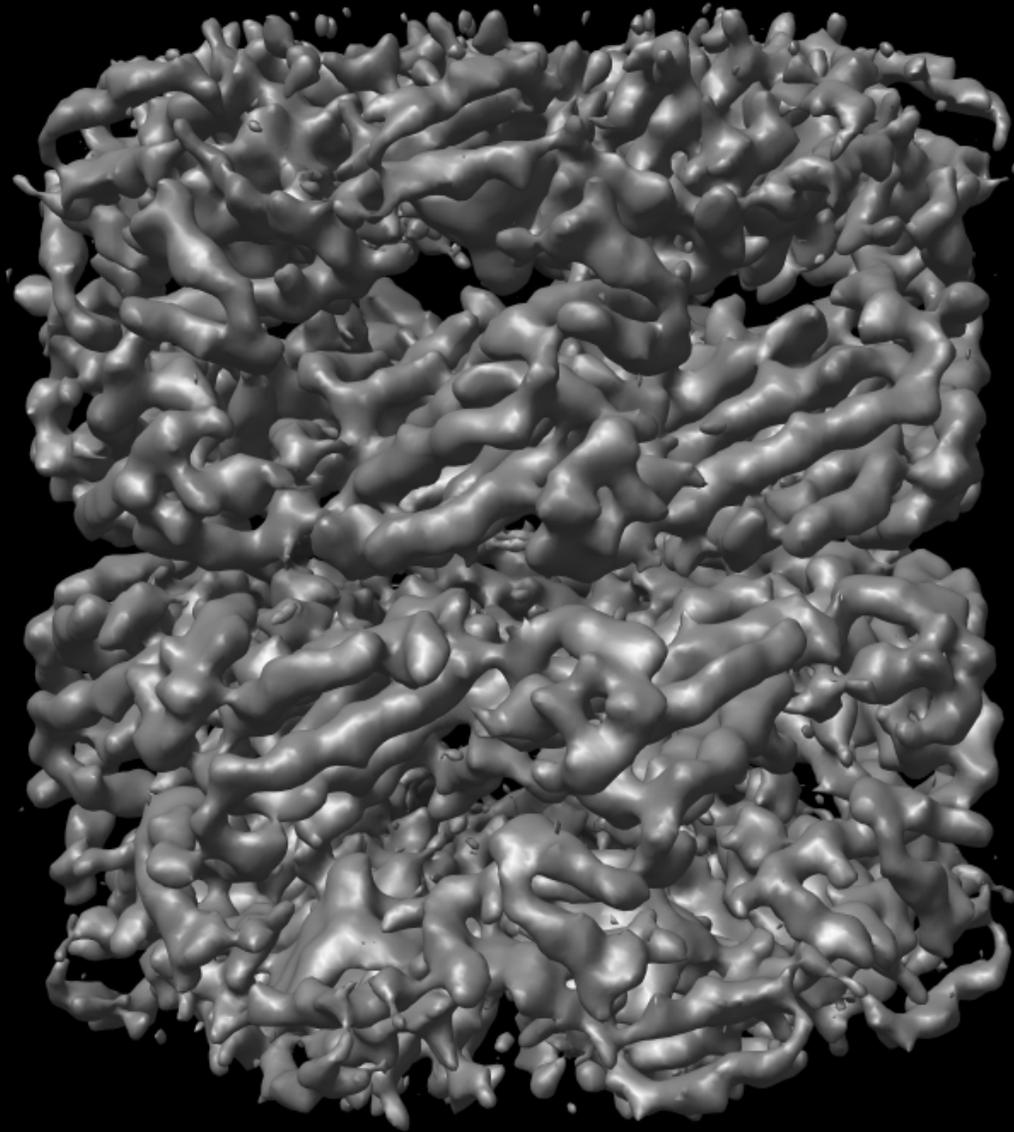
Resolution vs. Resolvability

- In optical microscopes and (most) telescopes
Resolution = Resolvability
- In electron microscopes, however,
Resolution \neq Resolvability
- In optical microscopes, resolvability is limited by wavelength+optics. This defines the resolution.
- Wavelength of a 100 keV electron is $\sim 0.05 \text{ \AA}$
- Electron optics can achieve sub- \AA resolvability
- **Noise** is the resolution limiting factor for biological specimens (radiation damage)!
- In SPA, resolution is a measure of Noise, **not** resolvability

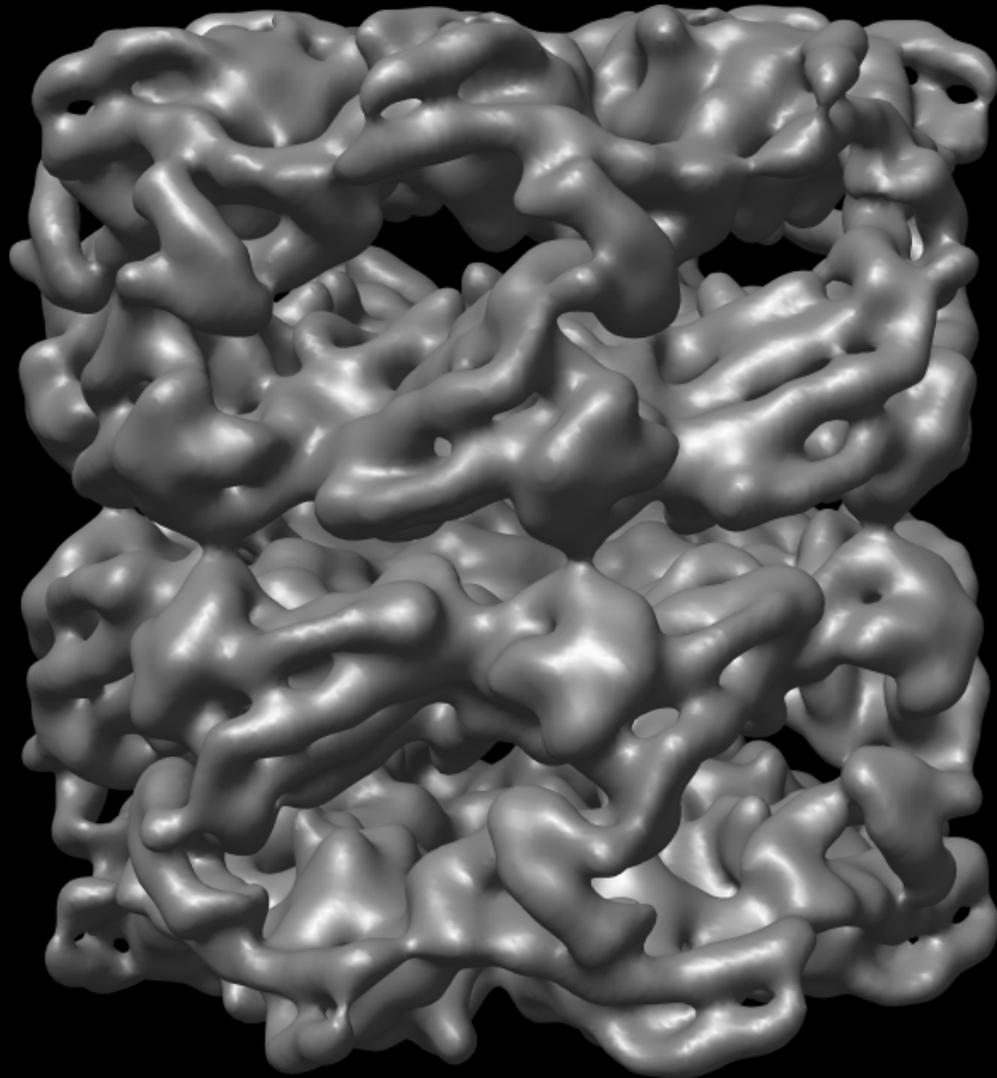
Measure Resolution ?

- ~~• Look at the model and see what features you can observe, ie – if you can see α -helices, you must have better than 8-10 Å resolution~~

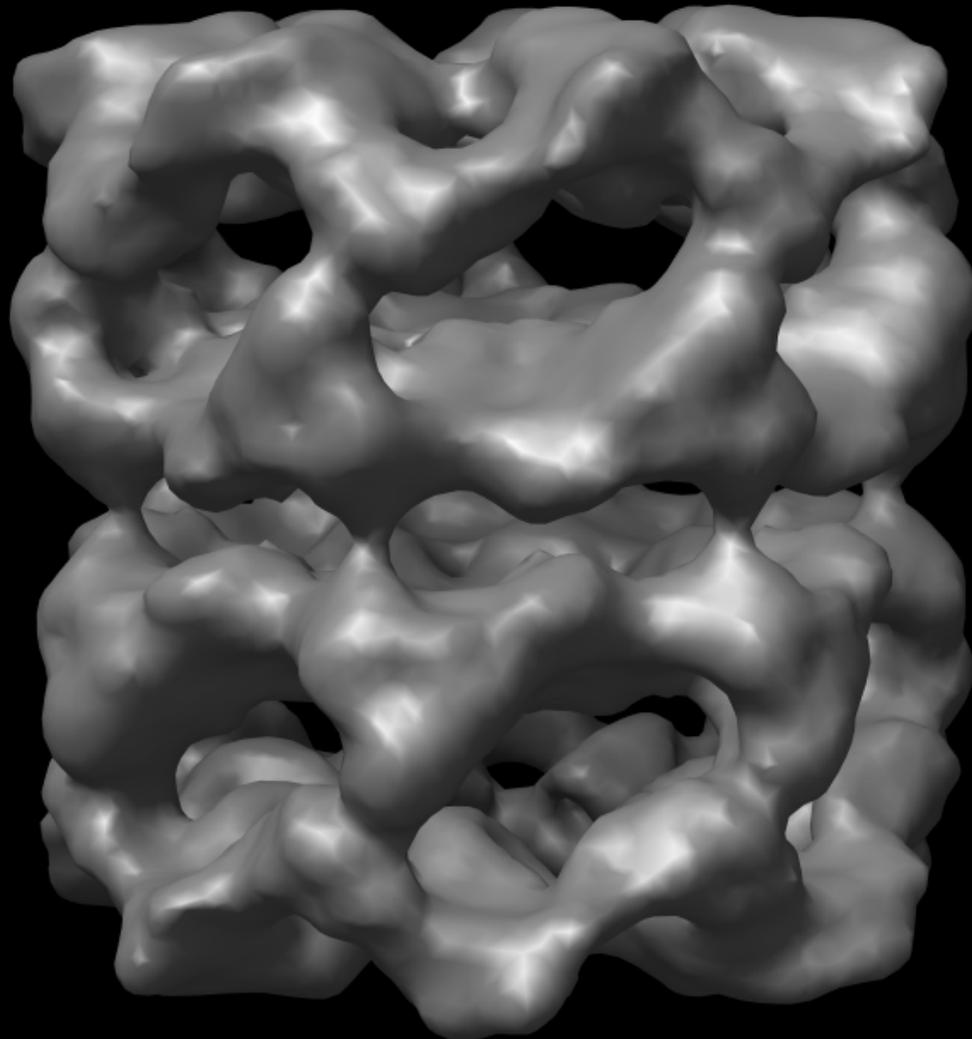
4 Å Resolution GroEL



4 Å \rightarrow 11.5 Å

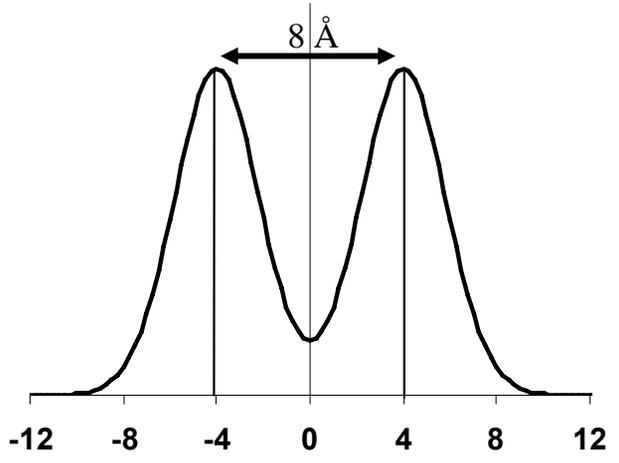


11.5 Å Resolution GroEL

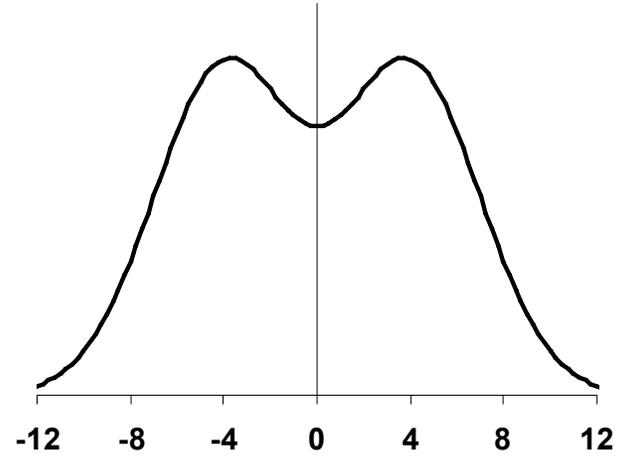


Resolution in Real Space

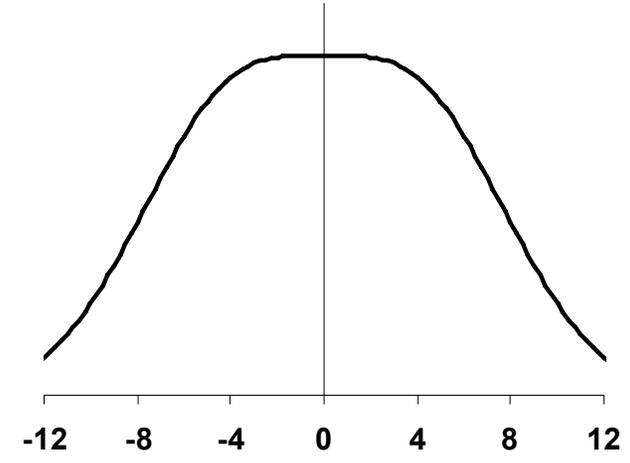
$$f(x) = e^{-\frac{2x^2}{a^2}}$$



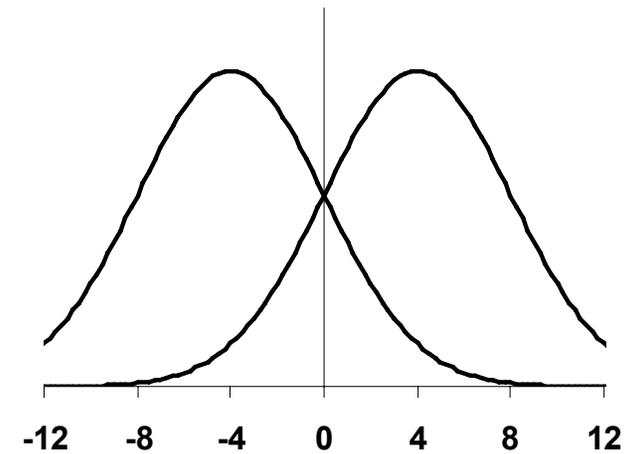
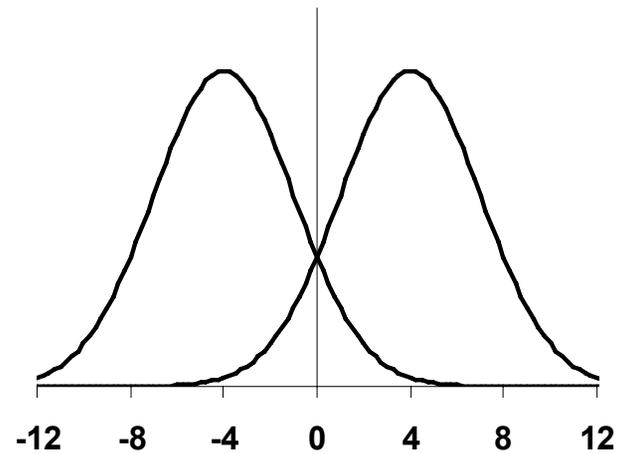
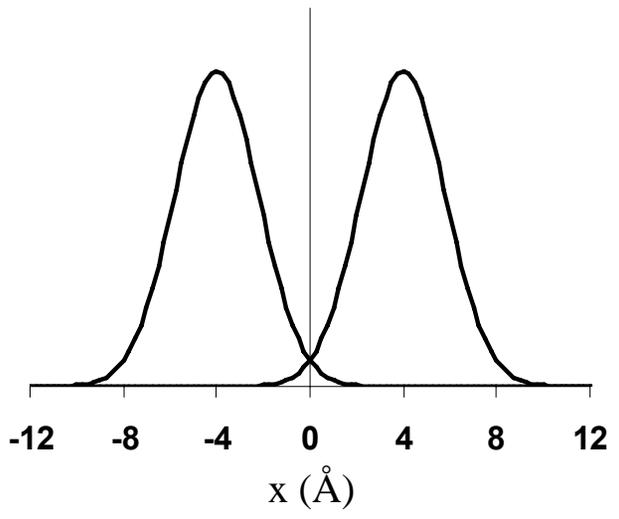
$$a = \frac{8\sqrt{2}}{\pi} = 3.6$$



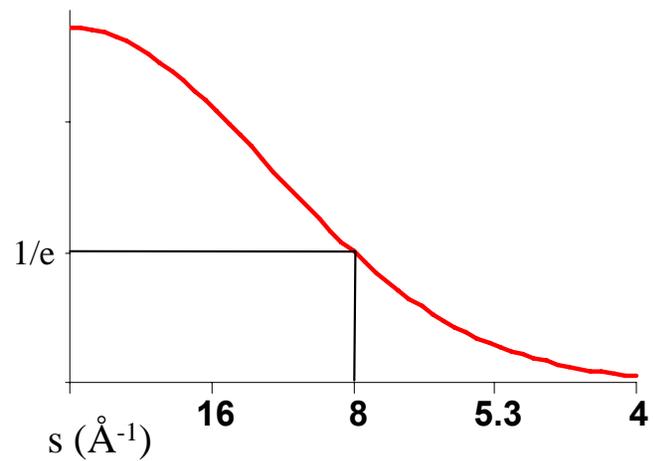
$$a = 6$$



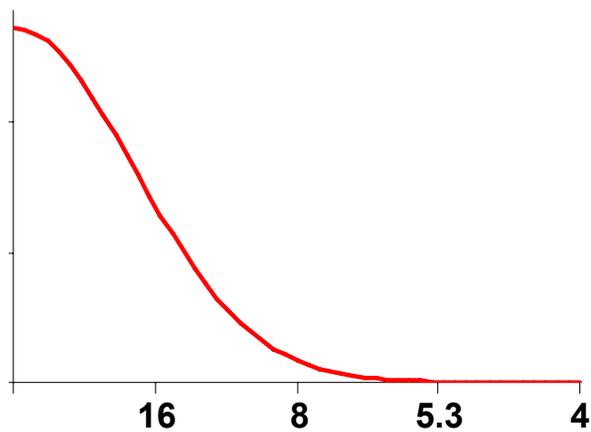
$$a = 8$$



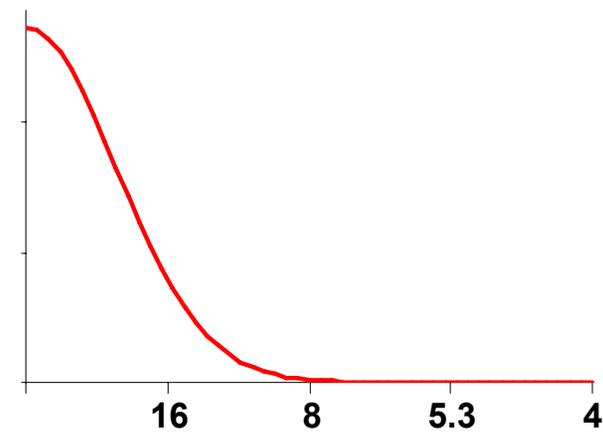
$$f(s) = e^{-\frac{1}{2}(\pi a s)^2}$$



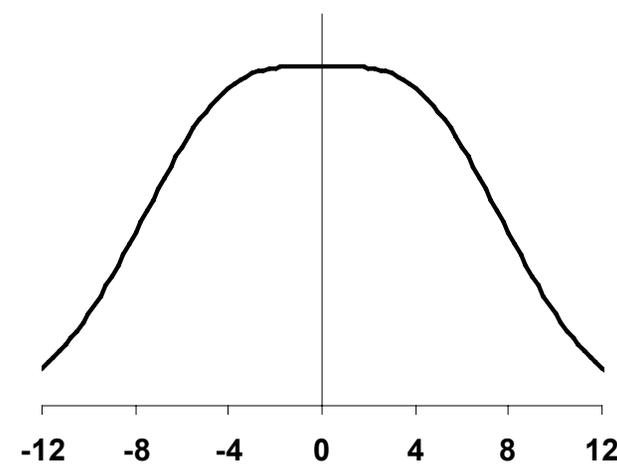
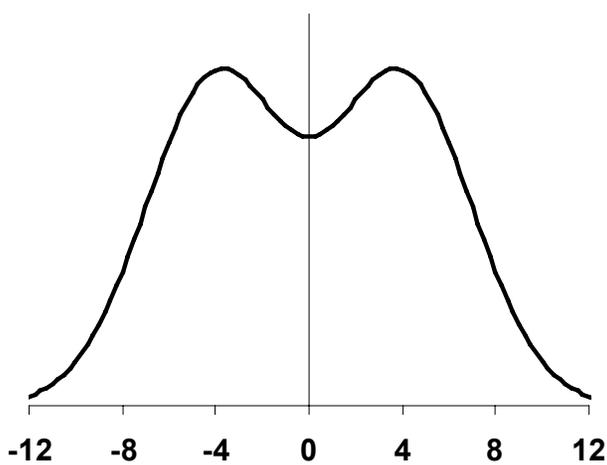
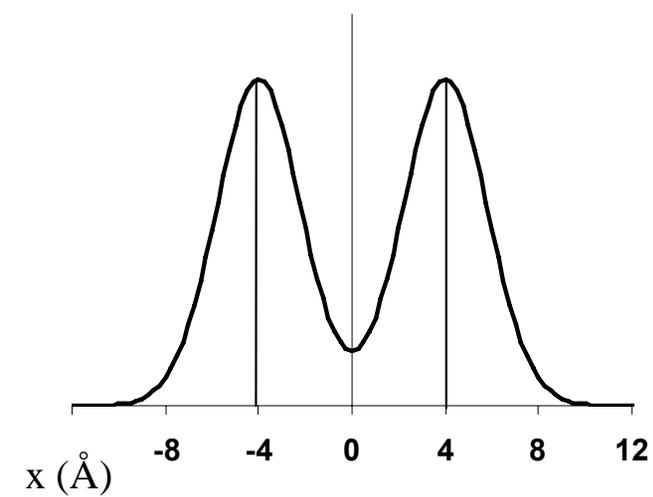
$$a = \frac{8\sqrt{2}}{\pi} = 3.6$$



$$a = 6$$



$$a = 8$$



$$f(x) = e^{-\frac{2x^2}{a^2}}$$

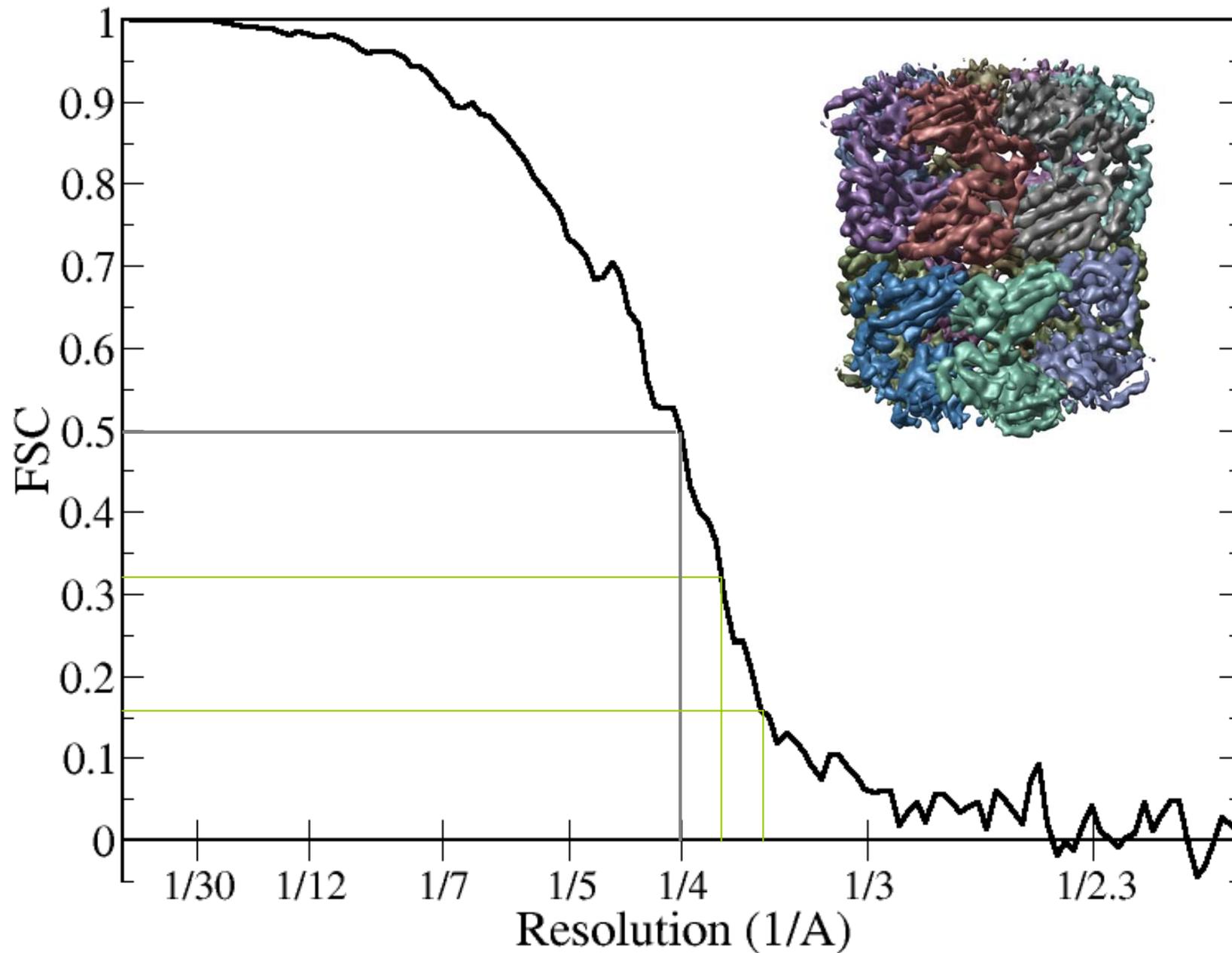
Measure Resolution

- Look at the statistical properties of our reconstruction.
- T-test ? Too expensive, and nonlinear response problems (bootstrapping).
- General practice: split particles into even and odd halves, reconstruct, compare models

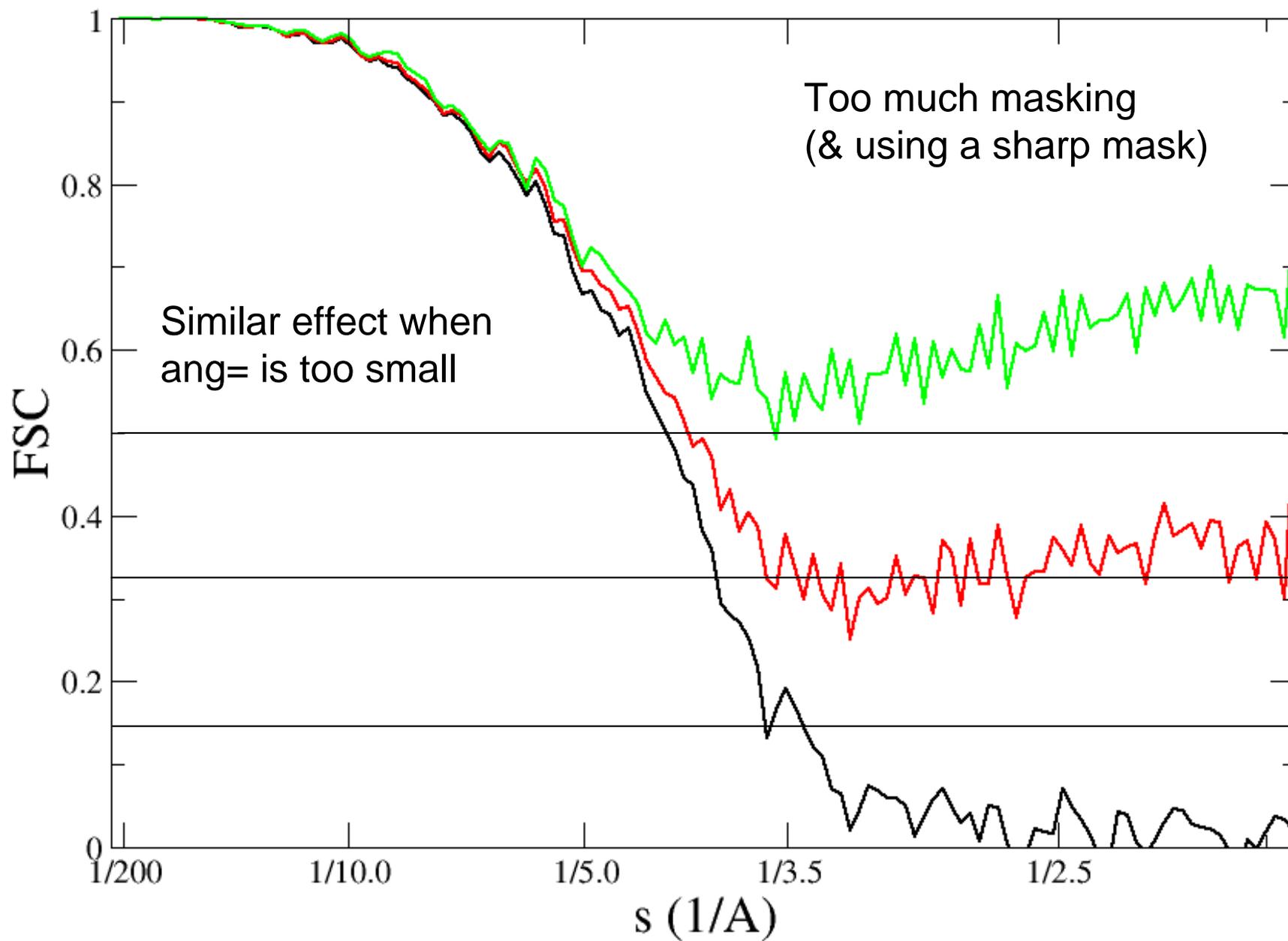
Compare Models ?

- Phase Residual
 - Definitions vary widely, causes meaning to be ambiguous
- Signal to Noise Ratio
 - Excellent properties. Additive (with perfect alignment). Counterintuitive threshold.
- Fourier Shell Correlation
 - Easy to compute. Sigmoidal curve with clearly defined value at most thresholds
 - What threshold to use ? (0.5, 0.33, 0.13, 3σ)

Good FSC

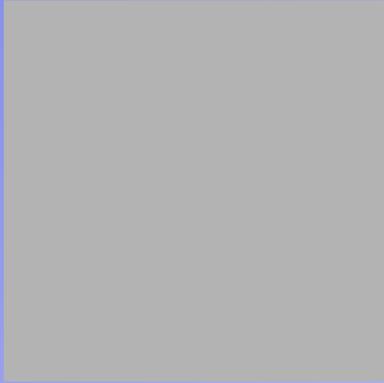


Bad FSC

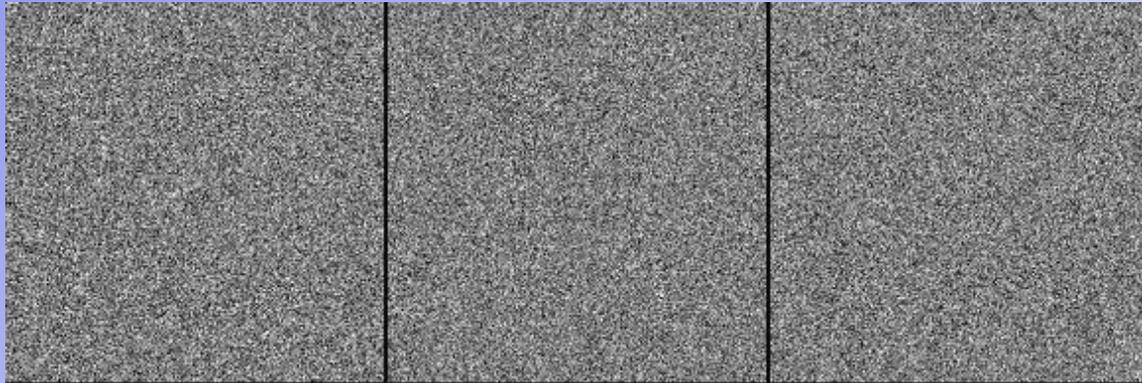


Model Bias

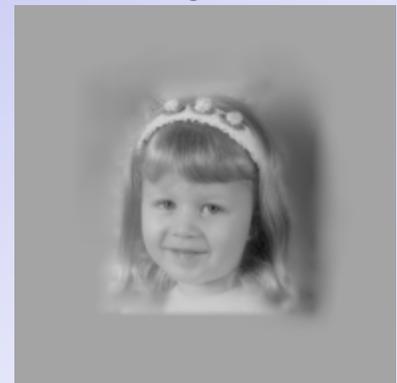
Base



Noisy



Align to



25

100

250

1000

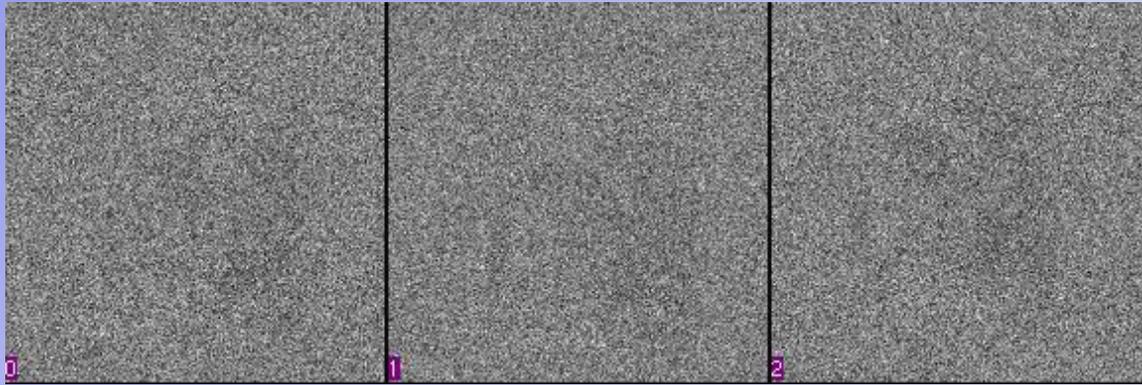
2000

Model Bias

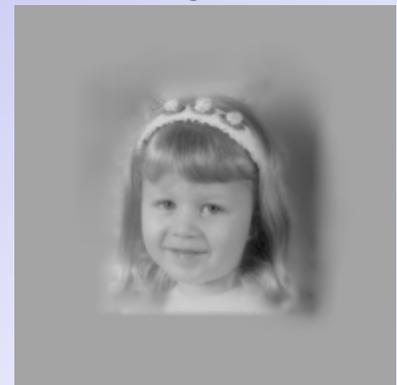
Base



Noisy (~10% contrast)



Align to



25

100

250

1000

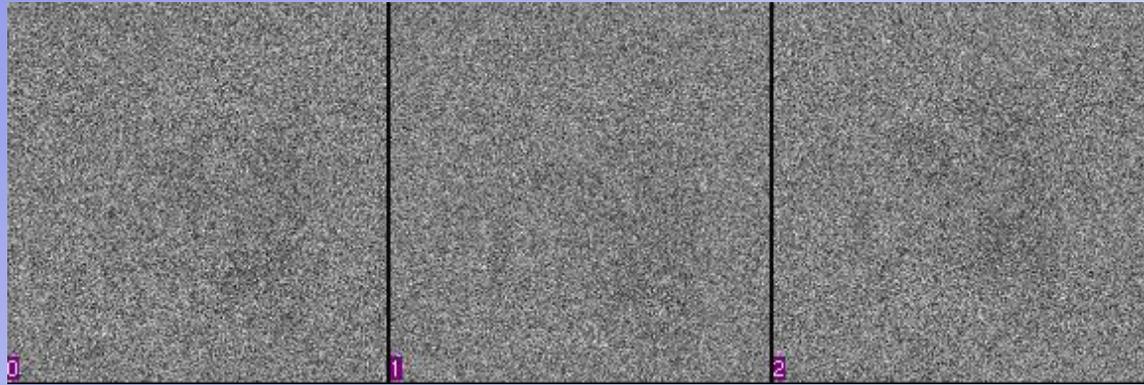
2000

Model Bias

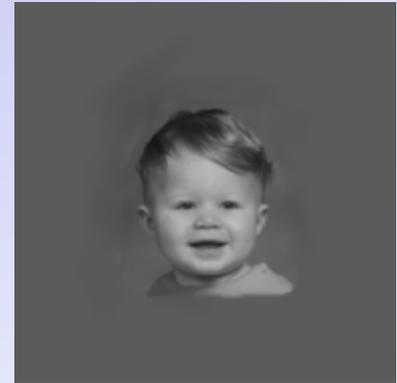
Base



Noisy (~10% contrast)



Align to



25

100

250

1000

2000

Model Bias

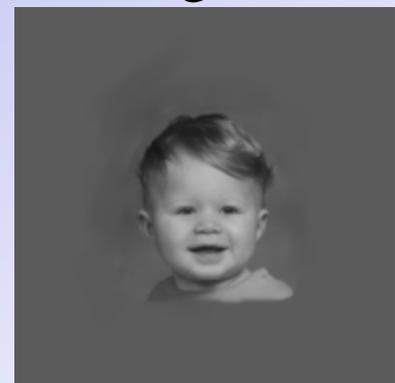
Base



Noisy



Align to



25

100

250

1000

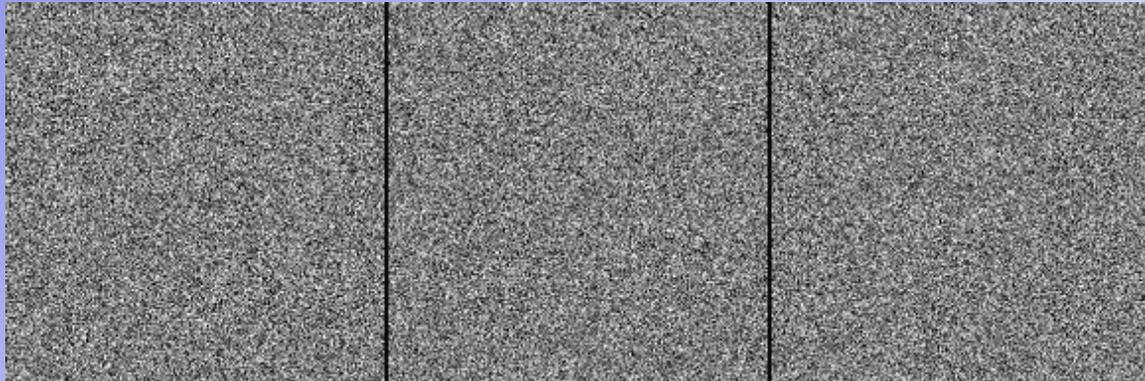
2000

Model Bias

Base

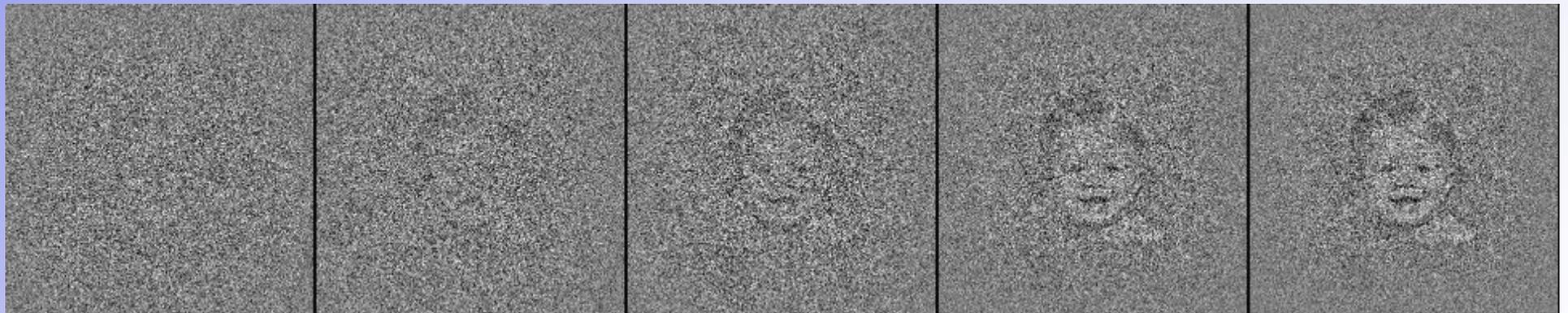


Noisy



Align to

Iter x4



25

100

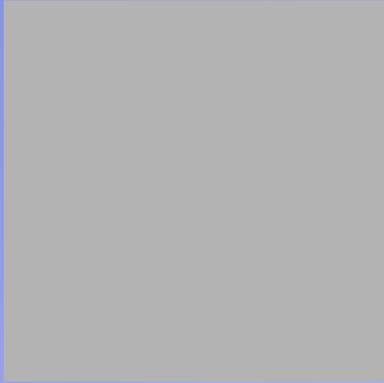
250

1000

2000

Model Bias

Base

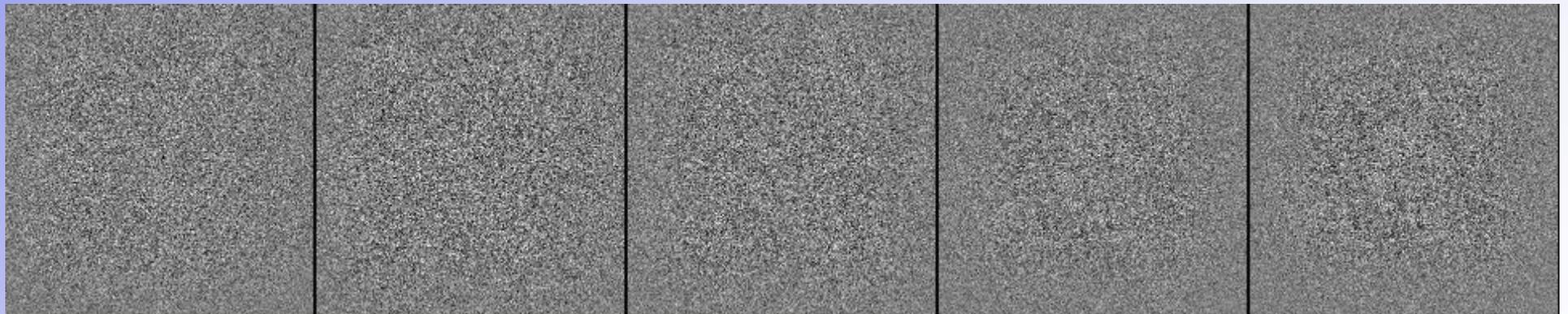


Noisy



Align to

Iter x8



25

100

250

1000

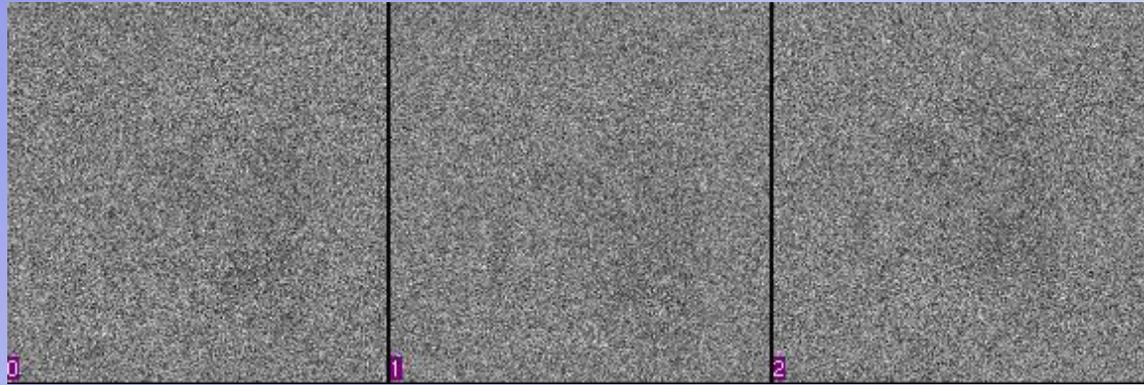
2000

Model Bias

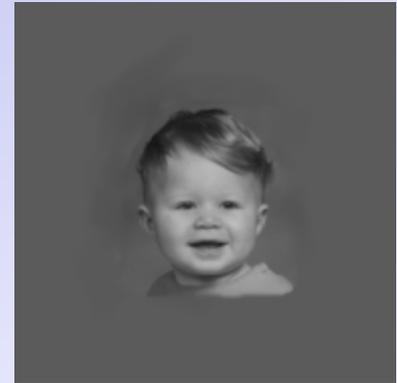
Base



Noisy (~10% contrast)



Align to



25

100

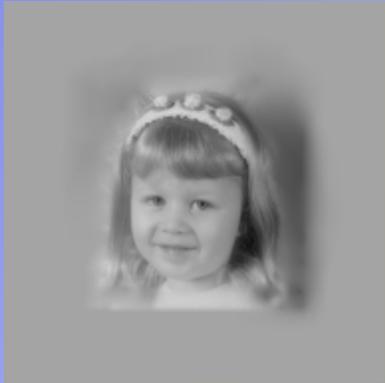
250

1000

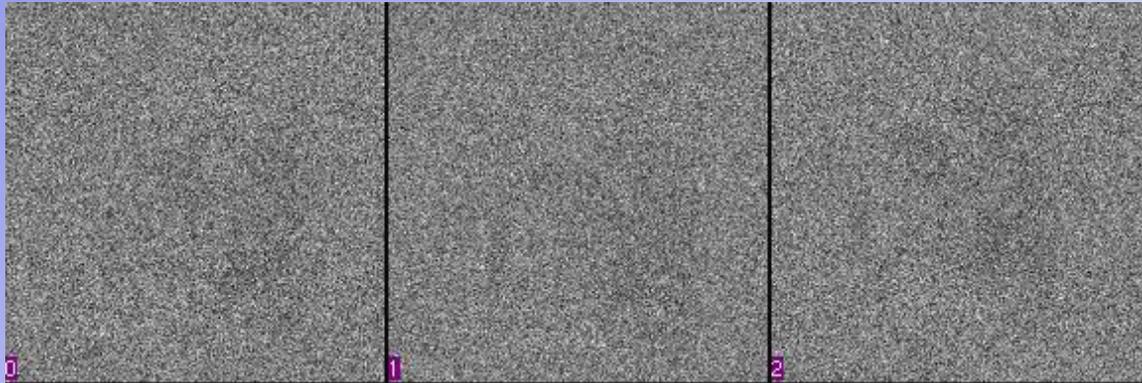
2000

Model Bias

Base



Noisy



Align to



Iter x4



25

100

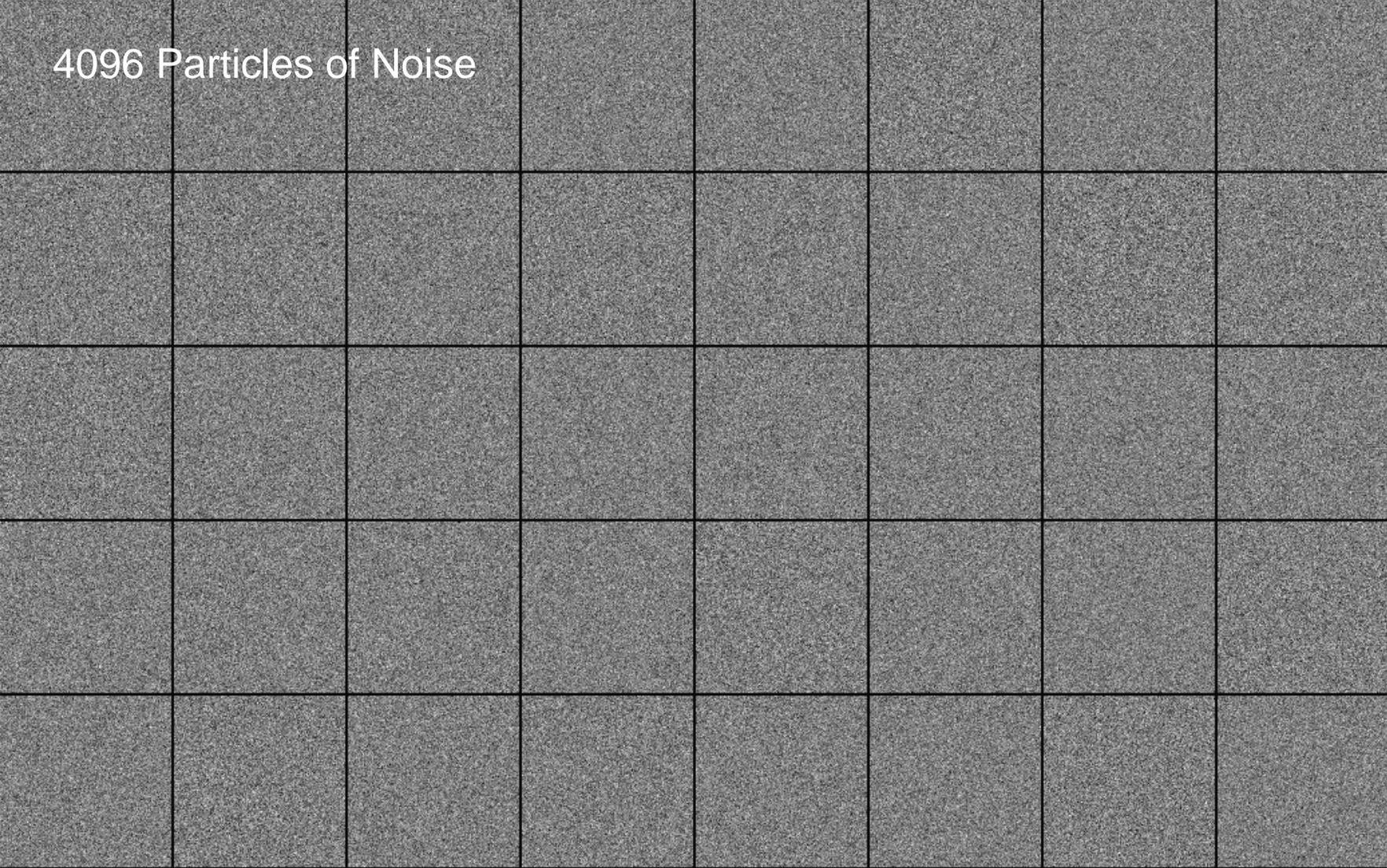
250

1000

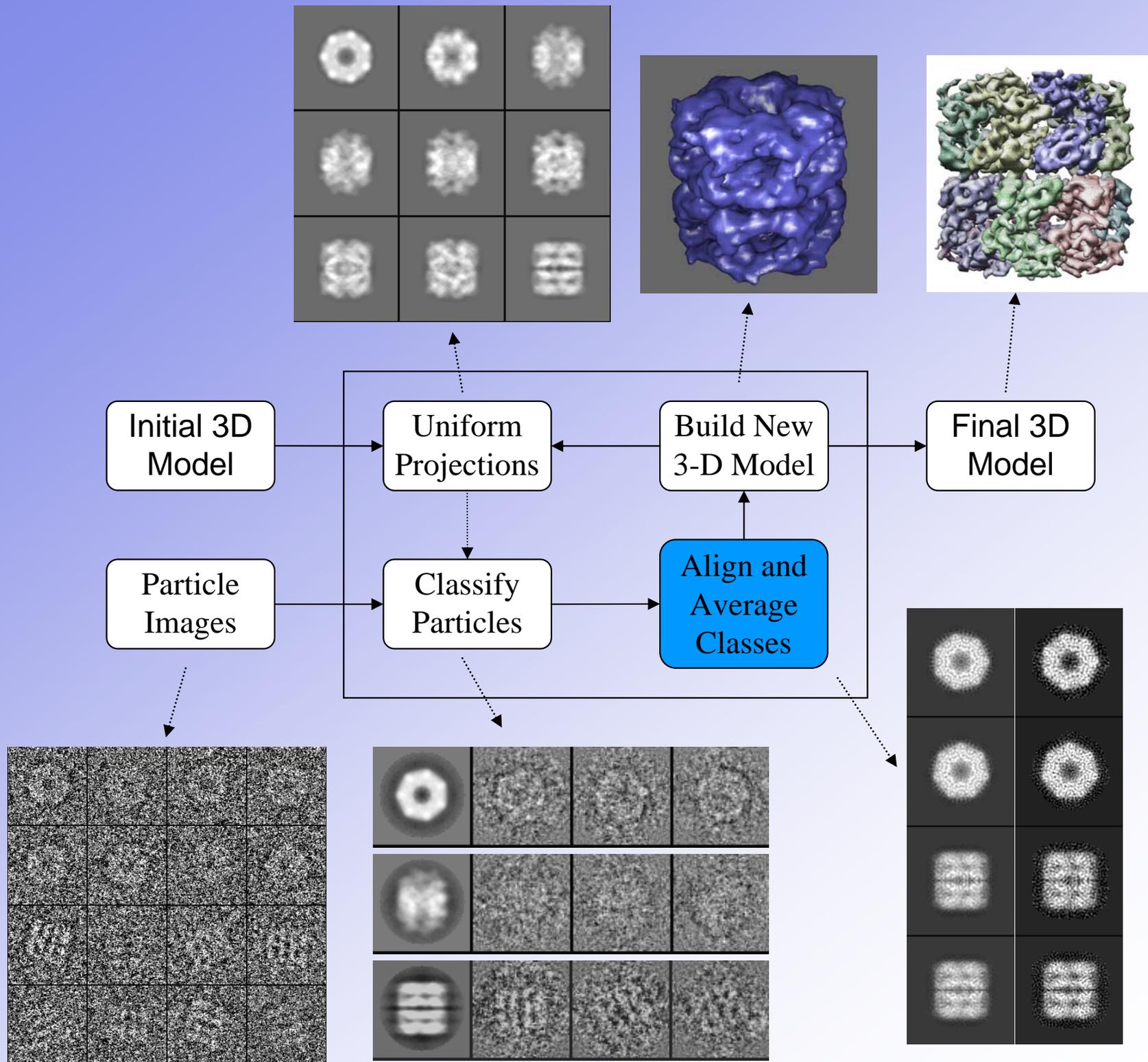
2000

How About 3-D ?

4096 Particles of Noise



refine 6 mask=56 hard=90 sym=d7 ang=1.6071 pad=160
xfiles=2,800,99 amask=15,.9,16 phasecls classkeep=10 sep=3

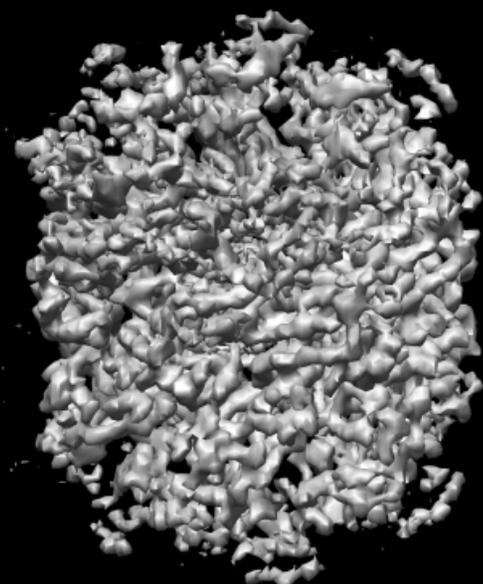
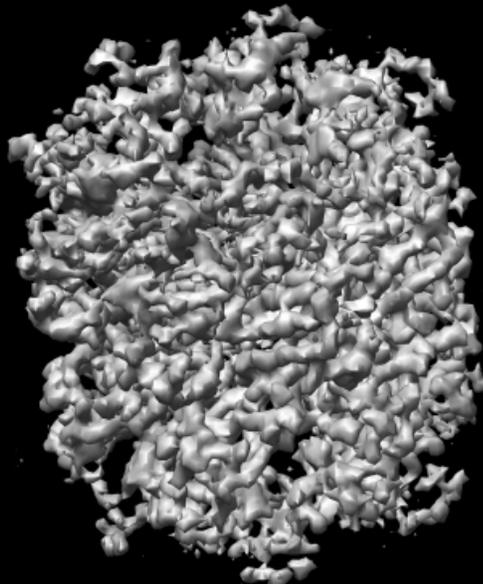
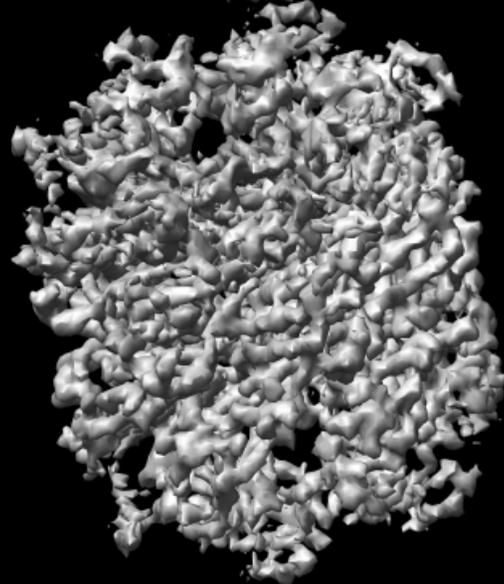
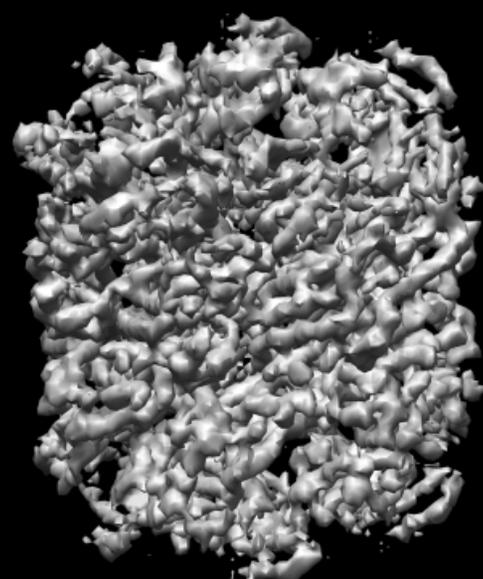
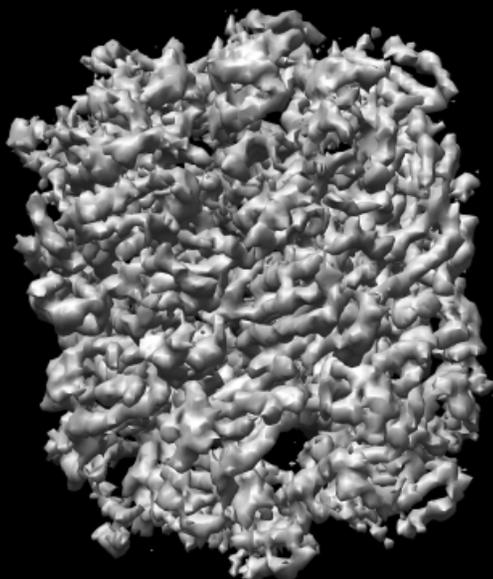
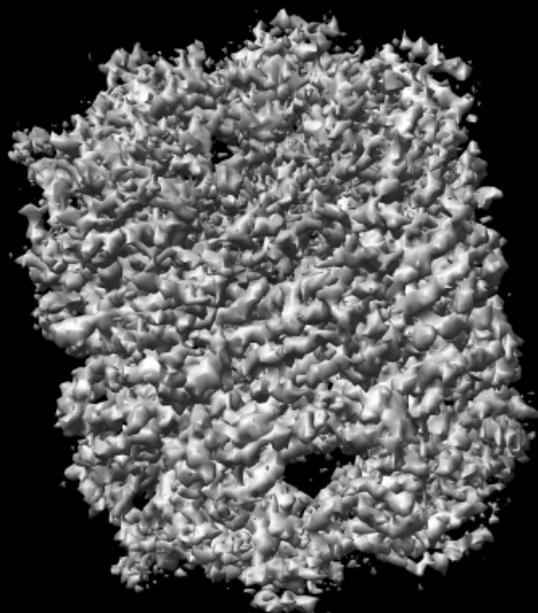


classiter=0

Initial Model

1 Iter.

2 Iter.

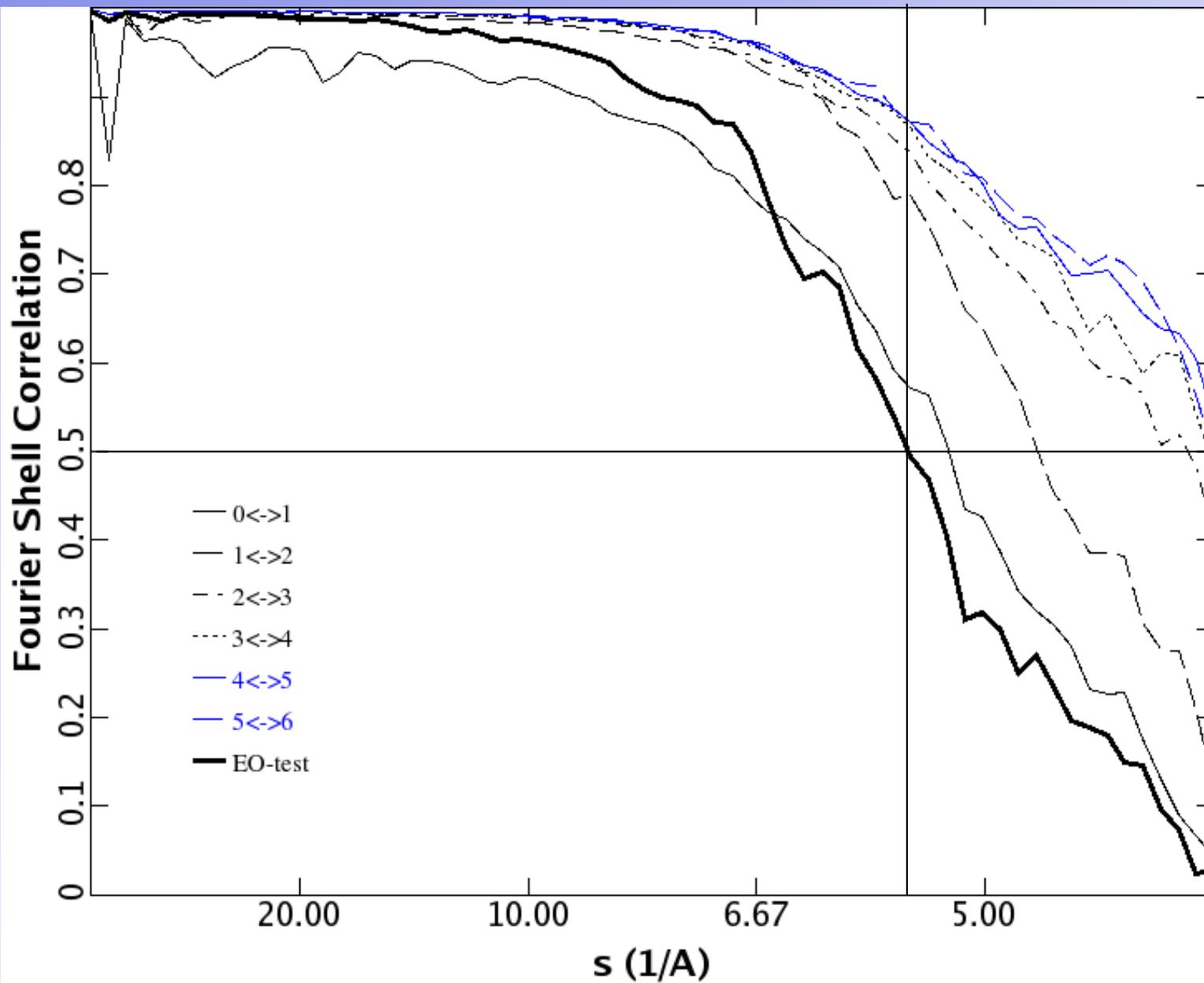


3 Iter.

4 Iter.

5 Iter.

Even Worse

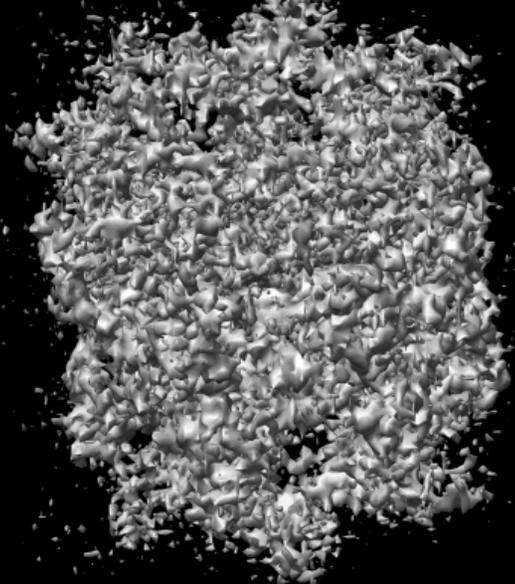
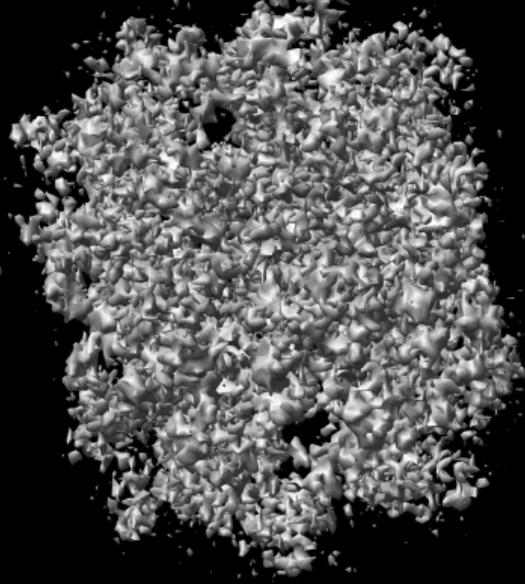
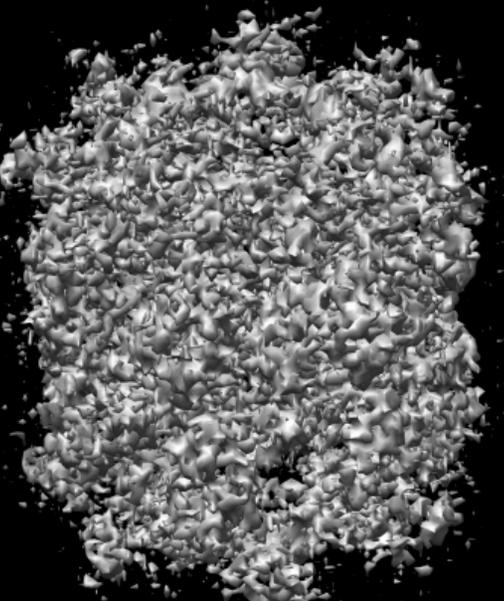
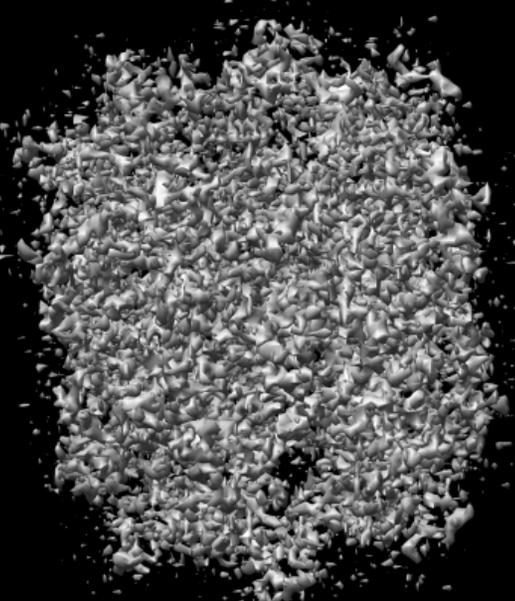
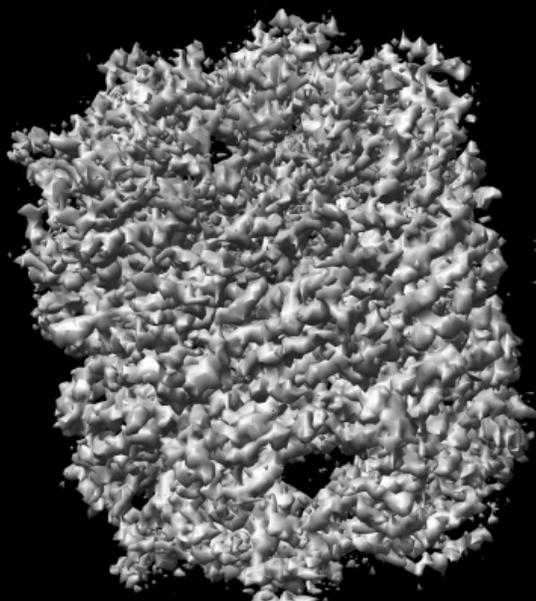


classiter=3

Initial Model

1 Iter.

2 Iter.



3 Iter.

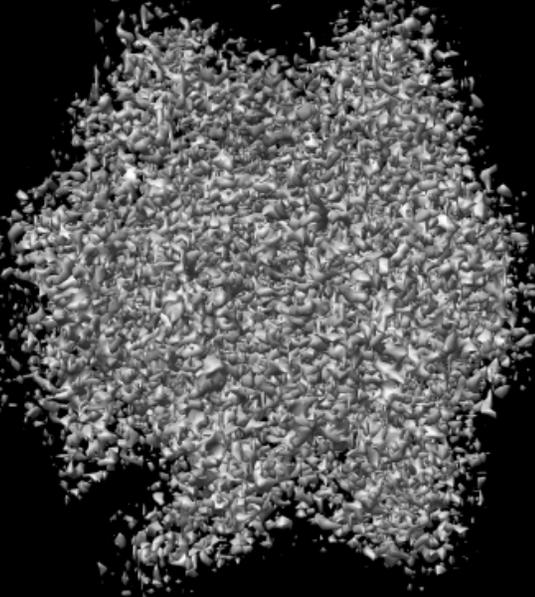
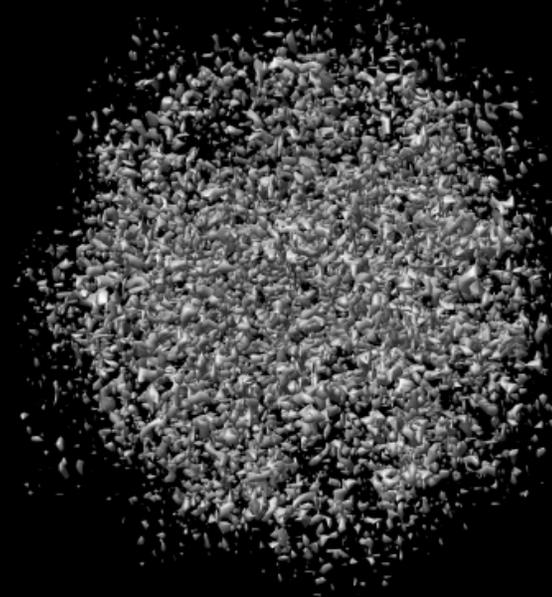
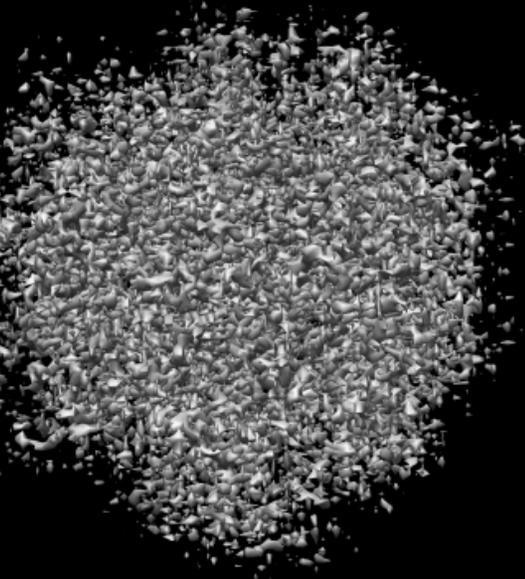
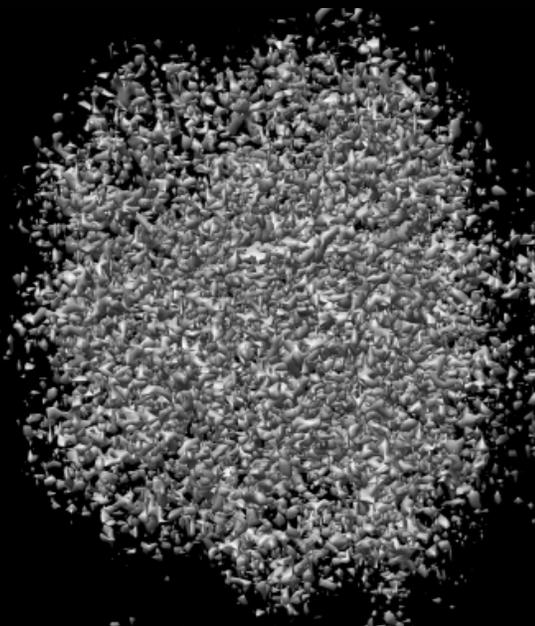
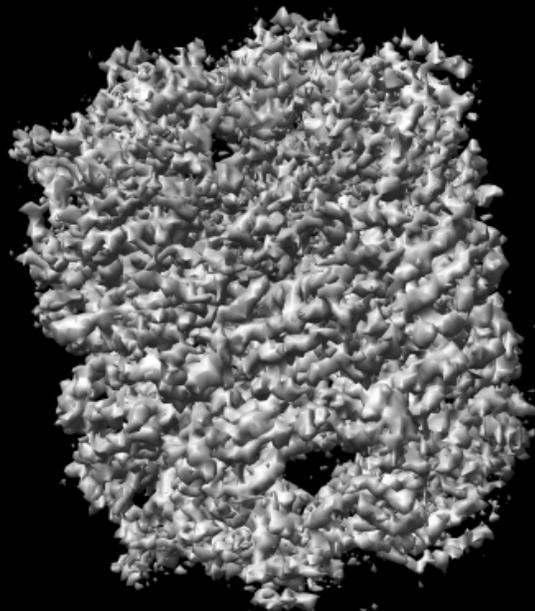
4 Iter.

classiter=8

Initial Model

1 Iter.

2 Iter.



3 Iter.

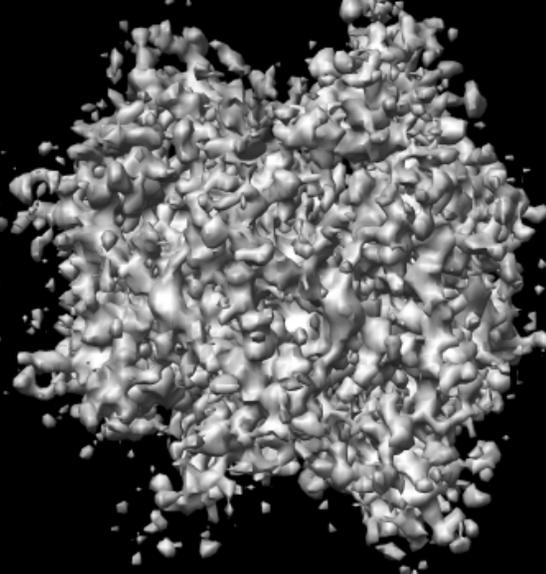
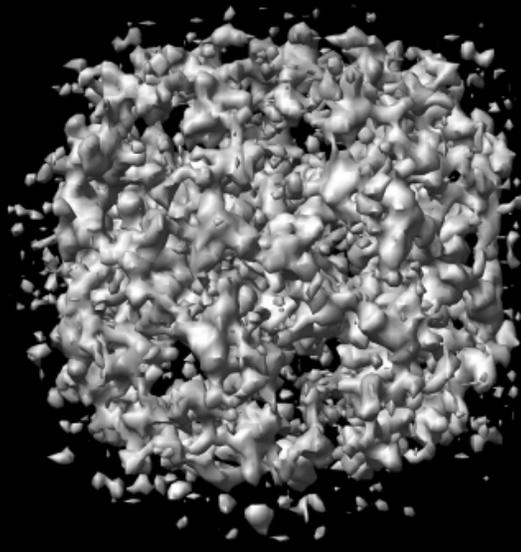
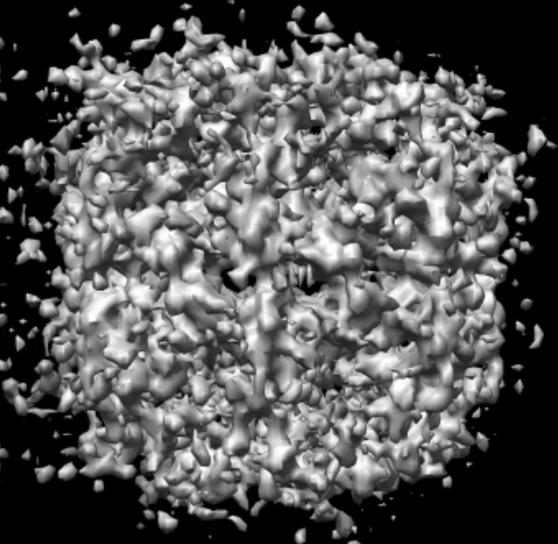
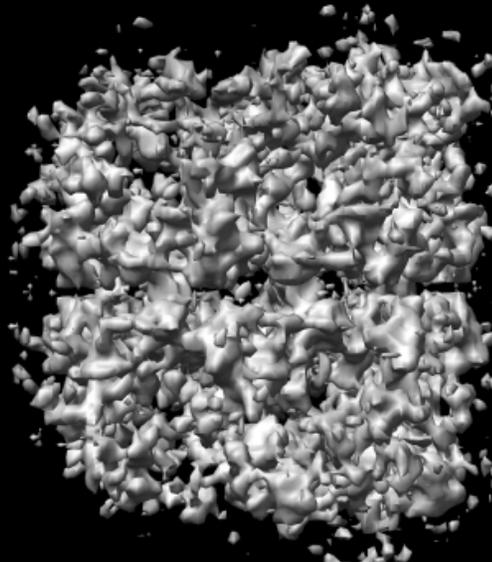
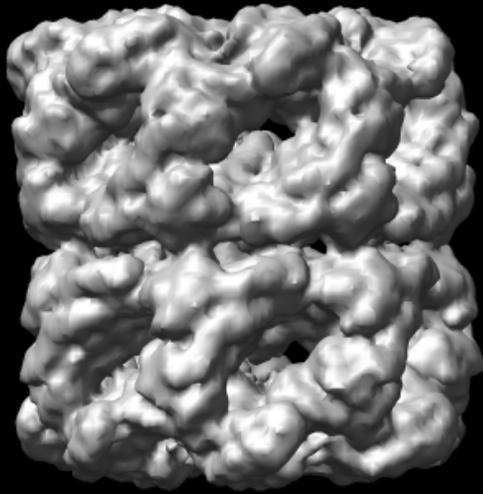
4 Iter.

classiter=8

(8 A lowpass) Initial Model

1 Iter.

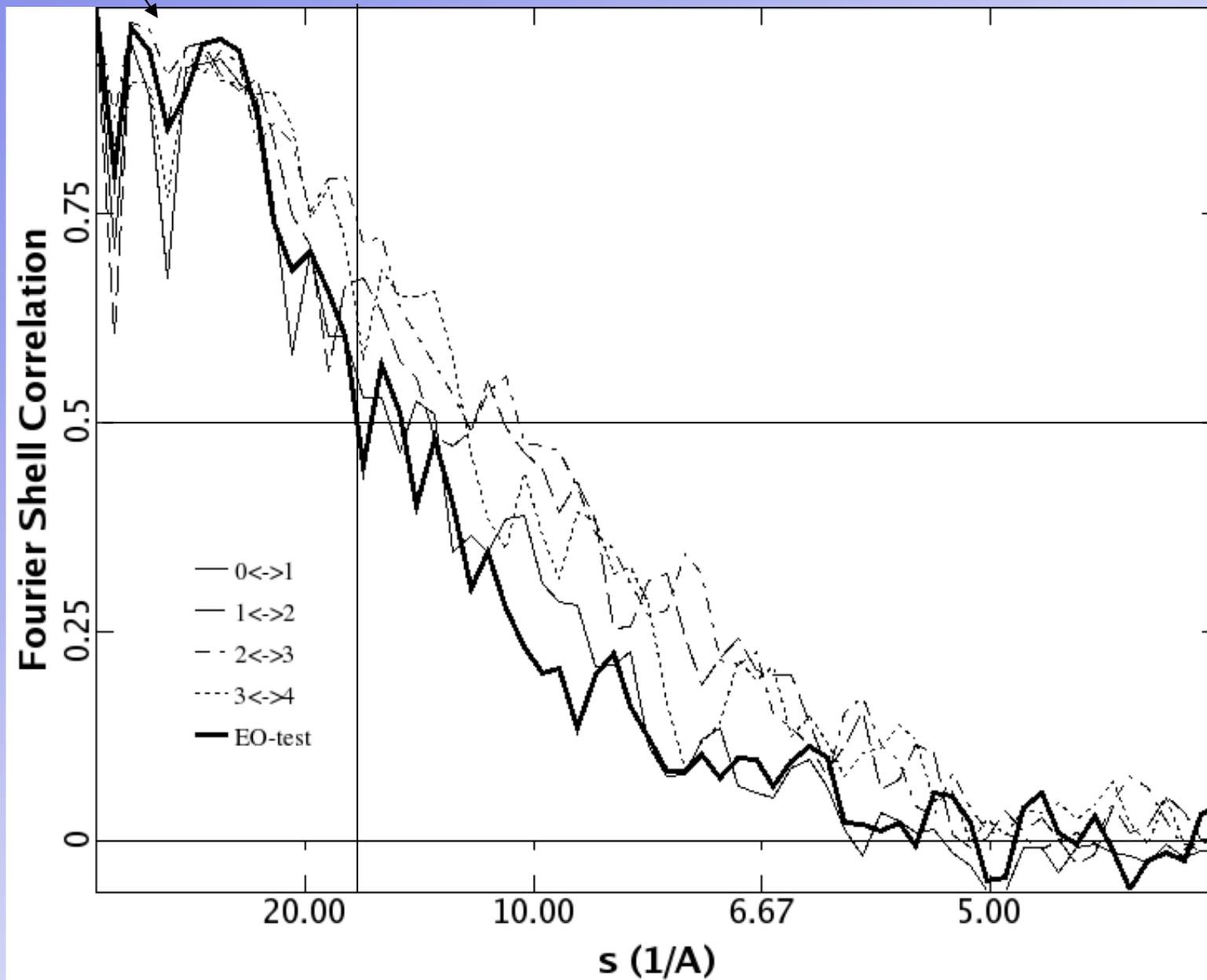
2 Iter.



3 Iter.

4 Iter.

Better...



How Do we Stop This ?

- Always start out with $\text{classiter} > 3$ for a few rounds
- Always refine from multiple starting models
- If the results are not effectively the same, try to establish which one is correct by looking at self consistency of projections/class-averages
- Make sure the features you are interpreting come out of all good refinements



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